

FORM PTO-1390
(REV 10-95)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTORNEY'S DOCKET NUMBER

**TRANSMITTAL LETTER TO THE UNITED STATES
DESIGNATED/ELECTED OFFICE (DO/EO/US)
CONCERNING A FILING UNDER 35 U.S.C. §371**

MERCK 2268

U.S. APPLICATION NO. (If known, see 37 CFR §1.5)

09/868866

INTERNATIONAL APPLICATION NO

INTERNATIONAL FILING DATE

PRIORITY DATE CLAIMED

PCT/EP99/09919

14 DECEMBER 1999

22 DECEMBER 1998

TITLE OF INVENTION


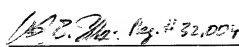
LIQUID-CRYSTALLINE MEDIUM

APPLICANT(S) FOR DO/EO/US

HECKMEIER, Michael, et al.

Applicant herewith submits to the United States Designated/Elected Office (DO/EO/US) the following items and other information:

1. ☒ This is a **FIRST** submission of items concerning a filing under 35 U.S.C. §371.
 2. ☐ This is a **SECOND** or **SUBSEQUENT** submission of items concerning a filing under 35 U.S.C. §371.
 3. ☐ This express request to begin national examination procedures (35 U.S.C. §371(f)) at any time rather than delay examination until the expiration of the applicable time limit set in 35 U.S.C. §371(b) and PCT Articles 22 and 39(1).
 4. ☒ A proper Demand for International Preliminary Examination was made by the 19th month from the earliest claimed priority date.
 5. ☒ A copy of the International Application as filed (35 U.S.C. §371(c)(2))
 - a. ☐ is transmitted herewith (required only if not transmitted by the International Bureau).
 - b. ☒ has been transmitted by the International Bureau.
 - c. ☐ is not required, as the application was filed in the United States Receiving Office (RO/US).
 6. ☐ A translation of the International Application into English (35 U.S.C. §371(c)(2)).
 7. ☒ Amendments to the claims of the International Application under PCT Article 19 (35 U.S.C. §371(c)(3))
 - a. ☐ are transmitted herewith (required only if not transmitted by the International Bureau).
 - b. ☐ have been transmitted by the International Bureau.
 - c. ☐ have not been made; however, the time limit for making such amendments has NOT expired.
 - d. ☒ have not been made and will not be made.
 8. ☐ A translation of the amendments to the claims under PCT Article 19 (35 U.S.C. §371(c)(3)).
 9. ☒ An oath or declaration of the inventor(s) (35 U.S.C. §371(c)(4)).
 10. ☐ A translation of the annexes to the International Preliminary Examination Report under PCT Article 36 (35 U.S.C. §371(c)(5)).
- Items 11. to 16. below concern document(s) or information included:**
11. ☐ An Information Disclosure Statement under 37 C.F.R. §§1.97 and 1.98.
 12. ☐ An assignment document for recording. A separate cover sheet in compliance with 37 C.F.R. §§3.28 and 3.31 is included.
 13. ☒ A FIRST preliminary amendment.
 - ☐ A SECOND or SUBSEQUENT preliminary amendment.
 14. ☐ A substitute specification.
 15. ☐ A change of power of attorney and/or address letter.
 16. ☐ Other items or information:

U.S. APPLICATION NO. <u>097868866</u>		INTERNATIONAL APPLICATION NO. <u>PCT/EP99/09919</u>		ATTORNEY'S DOCKET NUMBER <u>MERCK 2268</u>	
17. <input checked="" type="checkbox"/> The following fees are submitted:				CALCULATIONS PTO USE ONLY	
BASIC NATIONAL FEE (37 CFR §1.492 (a) (1) - (5)):					
Search Report has been prepared by the EPO or JPO.....				\$860.00	
International preliminary examination fee paid to USPTO (37 CFR §1.482).....				\$690.00	
No international preliminary examination fee paid to USPTO (37 CFR §1.482) but international search fee paid to USPTO (37 CFR §1.445(a)(2)).....				\$710.00	
Neither international preliminary examination fee (37 CFR §1.482) nor international search fee (37 CFR §1.445(a)(2)) paid to USPTO.....				\$1000.00	
International preliminary examination fee paid to USPTO (37 CFR §1.482) and all claims satisfied provisions of PCT Article 33(2)-(4).....				\$100.00	
ENTER APPROPRIATE BASIC FEE AMOUNT =				\$860.00	
Surcharge of \$130.00 for furnishing the oath or declaration later than months from the earliest claimed priority date (37 C.F.R. §1.492(e)). <input type="checkbox"/> 20 <input type="checkbox"/> 30					
CLAIMS	NUMBER FILED	NUMBER EXTRA	RATE		
Total claims	11 - 20 =	0	x \$ 18.00	\$0.00	
Independent claims	1 - 3 =	0	x \$ 80.00	\$0.00	
MULTIPLE DEPENDENT CLAIM(S) (if applicable)			+ \$ 270.00		
TOTAL OF ABOVE CALCULATIONS =				\$860.00	
Reduction of 1/2 for filing by small entity, if applicable. A Verified Small Entity Statement must also be filed (Note 37 C.F.R. §§1.9, 1.27, 1.28).					
SUBTOTAL =				\$860.00	
Processing fee of \$130.00 for furnishing the English translation later than months from the earliest claimed priority date (37 C.F.R. §1.492(f)). <input type="checkbox"/> 20 <input type="checkbox"/> 30					
TOTAL NATIONAL FEE =				\$860.00	
Fee for recording the enclosed assignment (37 C.F.R. §1.21(h)). The assignment must be accompanied by an appropriate cover sheet (37 C.F.R. §§3.28, 3.31). \$40.00 per property.					
TOTAL FEES ENCLOSED =				\$860.00	
				Amount to be refunded:	
				charged:	
a. <input checked="" type="checkbox"/> A check in the amount of \$860.00 to cover the above fees is enclosed.					
b. <input type="checkbox"/> Please charge my Deposit Account No. <u>13-3402</u> in the amount of \$_____ to cover the above fees. A duplicate copy of this sheet is enclosed.					
c. <input checked="" type="checkbox"/> The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment to Deposit Account No. <u>13-3402</u> . A duplicate copy of this sheet is enclosed.					
NOTE: Where an appropriate time limit under 37 C.F.R. §§1.494 or 1.495 has not been met, a petition to revive (37 C.F.R. §1.137(a) or (b)) must be filed and granted to restore the application to pending status.					
SEND ALL CORRESPONDENCE TO: Customer Number 23,599					
PATENT TRADEMARK OFFICE					
 <u>23599</u>					
Filed: 21 JUNE 2001					
AJZ:kmo					
 SIGNATURE <u>Anthony J. Zelano</u> NAME <u>27969</u> REGISTRATION NUMBER					

IN THE UNITED STATES DESIGNATED/ELECTED OFFICE

International Application No. : PCT/EP99/09919
International Filing Date : 14 DECEMBER 1999
Priority Date(s) Claimed : 22 DECEMBER 1998
Applicant(s) (DO/EO/US) : HECKMEIER, Michael, et al.

Title: LIQUID-CRYSTALLINE MEDIUM

PRELIMINARY AMENDMENT

Commissioner for Patents
Washington, D.C. 20231

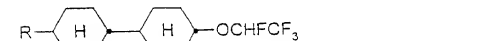
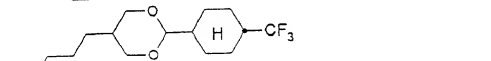
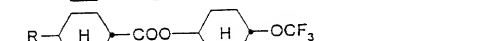
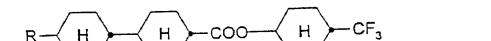
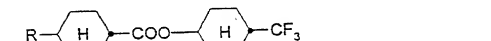
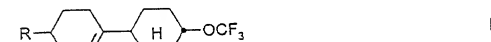
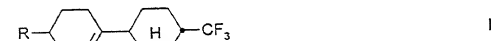
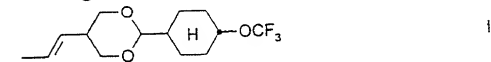
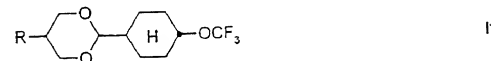
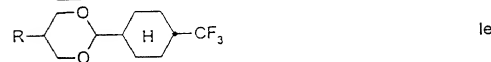
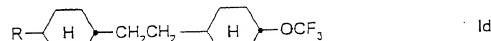
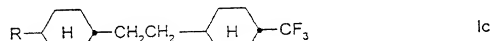
SIR:

Prior to calculating the national fee, and prior to examination in the National Phase of the above-identified International application, please amend as follows:

IN THE CLAIMS:

4. (Amended) Medium according to Claim 1, characterized in that the proportion of compounds of the formula I in the mixture as a whole is from 5 to 50% by weight.
5. (Amended) Medium according to Claim 2, characterized in that the proportion of compounds of the formulae II to VIII in the mixture as a whole is from 20 to 80% by weight.
7. (Amended) Medium according to Claim 2, characterized in that X⁰ is F or OCF₃, and Y² is H or F.
8. (Amended) Medium according to Claim 1, characterized in that, in the compound of the formula I, Y is OCF₃ or CF₃.

9. (Amended) Medium according to Claim 1, characterized in that the compound of the formula I is selected from the group consisting of the compounds Ia to In:



in which R is as defined in Claim 1.

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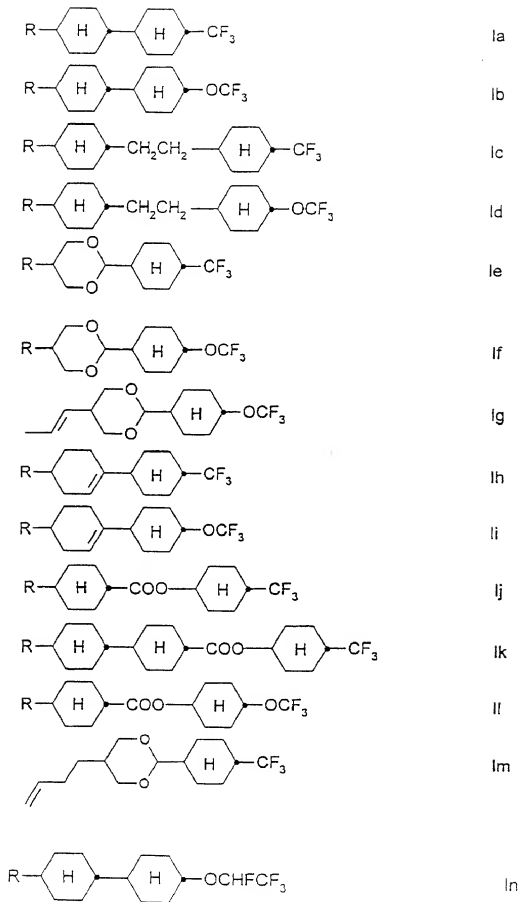
- 4 -

MERCK 2268

VERSION WITH MARKINGS TO SHOW CHANGES MADE

Claims 4-5 and 7-9 have been amended as follows:

4. (Amended) Medium according to Claim 1-~~or~~2, characterized in that the proportion of compounds of the formula I in the mixture as a whole is from 5 to 50% by weight.
5. (Amended) Medium according to ~~at least one of~~ Claims 2-~~to~~3, characterized in that the proportion of compounds of the formulae II to VIII in the mixture as a whole is from 20 to 80% by weight.
7. (Amended) Medium according to Claim 2-~~or~~ Claim 6, characterized in that X^0 is F or OCF_3 , and Y^2 is H or F.
8. (Amended) Medium according to ~~one of~~ Claims 1-~~to~~7, characterized in that, in the compound of the formula I, Y is OCF_3 or CF_3 .
9. (Amended) Medium according to ~~one of~~ Claims 1-~~to~~8, characterized in that the compound of the formula I is selected from the group consisting of the compounds Ia to In:



in which R is as defined in Claim 1.

APPLICATION DATA SHEET

APPLICATION INFORMATION

Application Type::	REGULAR
Subject Matter::	UTILITY
CD-ROM or CD-R?::	NONE
Title::	LIQUID-CRYSTALLINE MEDIUM
Attorney Docket Number::	MERCK 2268

INVENTOR INFORMATION

Inventor Authority Type::	INVENTOR
Primary Citizenship Country::	Germany
Status::	FULL CAPACITY
Given Name::	Michael
Family Name::	HECKMEIER
City of Residence::	Bensheim
Country of Residence::	Germany
Street::	Bahnhofstrasse 14
City::	Bensheim
Country::	Germany
Postal or Zip Code::	D-64625

Inventor Authority Type::	INVENTOR
Primary Citizenship Country::	Germany
Status::	FULL CAPACITY
Given Name::	Brigitte
Family Name::	SCHULER
City of Residence::	Haibach
Country of Residence::	Germany
Street::	Blumenstrasse 13
City::	Haibach
Country::	Germany
Postal or Zip Code::	D-63808

Inventor Authority Type::	INVENTOR
Primary Citizenship Country::	JAPAN
Status::	FULL CAPACITY
Given Name::	Kazuaki
Family Name::	TARUMI
City of Residence::	Seeheim
Country of Residence::	Germany
Street::	Fliederweg 29
City::	Seeheim
Country::	Germany
Postal or Zip Code::	D-64342

Initial 06/21/01

Liquid-crystalline medium

The present invention relates to a liquid-crystalline medium, and to the use thereof for electro-optical purposes, and to displays containing this medium.

Liquid-crystals are used principally as dielectrics in display devices, since the optical properties of such substances can be modified by an applied voltage.

10 Electro-optical devices based on liquid crystals are extremely well known to the person skilled in the art and can be based on various effects. Examples of such devices are cells having dynamic scattering, DAP (deformation of aligned phases) cells, guest/host

15 cells, TN cells having a twisted nematic structure, STN (supertwisted nematic) cells, SBE (superbirefringence effect) cells and OMI (optical mode interference) cells. The commonest display devices are based on the Schadt-Helfrich effect and have a twisted nematic

20 structure.

The liquid-crystal materials must have good chemical and thermal stability and good stability to electric fields and electromagnetic radiation. Furthermore, the

25 liquid-crystal materials should have low viscosity and produce short addressing times, low threshold voltages and high contrast in the cells.

They should furthermore have a suitable mesophase, for

30 example a nematic or cholesteric mesophase for the abovementioned cells, in the usual operating temperatures, i.e. in the broadest possible range above and below room temperature. Since liquid crystals are generally used as mixtures of a plurality of

35 components, it is important that the components are readily miscible with one another. Further properties, such as the electrical conductivity, the dielectric anisotropy and the optical anisotropy, must satisfy various requirements depending on the cell type and

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area of application. For example, materials for cells having a twisted nematic structure should have positive dielectric anisotropy and low electrical conductivity.

- 5 For example, media having large positive dielectric anisotropy, broad nematic phases, relatively low birefringence, very high specific resistance, good UV and temperature stability and low vapour pressure are desired for matrix liquid-crystal displays containing
10 integrated non-linear elements for switching individual pixels (MLC displays).

Matrix liquid-crystal displays of this type are known. Non-linear elements which can be used for individual
15 switching of the individual pixels are, for example, active elements (i.e. transistors). Reference is then made to an "active matrix", where a distinction can be made between two types:

- 20 1. MOS (metal oxide semiconductor) or other diodes on a silicon wafer as substrate.
2. Thin-film transistors (TFTs) on a glass plate as substrate.

25 The use of monocrystalline silicon as substrate material restricts the display size, since even modular assembly of various part-displays results in problems at the joints.

30 In the case of more-promising type 2, which is preferred, the electro-optical effect used is usually the TN effect. A distinction is made between two technologies: TFTs comprising compound semiconductors, such as, for
35 example, CdSe or TFTs based on polycrystalline or amorphous silicon. The latter technology is being worked on intensively worldwide.

The TFT matrix is applied to the inside of one glass plate of the display, while the other glass plate carries the transparent counterelectrode on its inside. In contrast to the size of the pixel electrode, the TFT is very small and has virtually no interfering effect on the image. This technology can also be expanded to fully colour-compatible displays, in which a mosaic of red, green and blue filters is arranged in such a way that a filter element is opposite each switchable pixel.

The TFT displays usually operate as TN cells with crossed polarizers in transmission and are illuminated from the back.

The term MLC displays here covers any matrix display containing integrated non-linear elements, i.e., besides the active matrix, also displays containing passive elements, such as varistors or diodes (MIM = metal-insulator-metal).

MLC displays of this type are particularly suitable for TV applications (for example pocket TVs) or for high-information displays for computer applications (laptops) and in automobile or aircraft construction. Besides problems regarding the angle dependence of the contrast and the response times, difficulties also arise in MLC displays due to the insufficiently high specific resistance of the liquid-crystal mixtures [TOGASHI, S., SEKIGUCHI, K., TANABE, H., YAMAMOTO, E., SORIMACHI, K., TAJIMA, E., WATANABE, H., SCHIMIZU, H., Proc. Eurodisplay 84, Sept. 1984: A 210-288 Matrix LCD Controlled by Double Stage Diode Rings, p. 141 ff, Paris; STROMER, M., Proc. Eurodisplay 84, Sept. 1984: Design of Thin Film Transistors for Matrix Addressing of Television Liquid Crystal Displays, p. 145 ff, Paris]. With decreasing resistance, the contrast of a MLC display worsens, and the problem of after-image elimination can occur. Since the specific resistance of

the liquid-crystal mixture generally drops over the life of an MLC display owing to interaction with the interior surfaces of the display, a high (initial) resistance is very important in order to obtain acceptable service lives. In particular in the case of low-volt mixtures, it was hitherto impossible to achieve very high specific resistance values. It is furthermore important that the specific resistance exhibits the smallest possible increase with increasing temperature and after heating and/or UV exposure. The low-temperature properties of the mixtures of the prior art are also particularly disadvantageous. The demands are that no crystallization and/or smectic phases occur, even at low temperatures, and the temperature dependence of the viscosity is as low as possible. The MLC displays from the prior art thus do not meet today's requirements.

Besides liquid-crystal displays which use back illumination, i.e. are operative transmissively and optionally transreflectively, there is also particular interest in reflective liquid-crystal displays. These reflective liquid-crystal displays use the ambient light for information display. They thus consume significantly less energy than back-illuminated liquid-crystal displays of corresponding size and resolution. Since the TN effect is characterized by very good contrast, reflective displays of this type are readily legible even under bright ambient conditions. This is already known of simple reflective TN displays, as used, for example, in wristwatches and pocket calculators. However, the principle can also be applied to high-quality, higher-resolution active matrix-addressed displays, such as, for example, TFT displays. Here, as is already the case in the generally conventional transmissive TFT-TN displays, the use of liquid crystals of low birefringence (Δn) is necessary in order to achieve low optical retardation ($d \cdot \Delta n$). This low optical retardation results in a low viewing-angle

dependence of the contrast, which is usually acceptable (cf. DE 30 22 818). In reflective displays, the use of liquid crystals of low birefringence is much more important than in transmissive displays, since in reflective displays, the effective layer thickness, through which the light passes, is approximately twice as large as in transmissive displays of the same layer thickness.

- 10 Besides the lower power consumption (no back-illumination necessary), other advantages of reflective displays over transmissive displays are the space saving, which results in a very low installation depth, and the reduction in problems caused by temperature
- 15 gradients due to various heating by the back-illumination.

- There thus continues to be a great demand for MLC displays having very high specific resistance at the same time as a large working-temperature range, short response times even at low temperatures and low threshold voltage which do not have these disadvantages, or only do so to a reduced extent.
- 20

- 25 In TN (Schadt-Helfrich) cells, media are desired which facilitate the following advantages in the cells:

- expanded nematic phase range (in particular down to low temperatures)
- 30
- switching at extremely low temperatures (outdoor use, automobile, avionics)
 - increased resistance to UV radiation (longer life)
- 35
- lower threshold (addressing) voltage
 - low birefringence, especially for improved viewing-angle range.

The media available from the prior art do not allow these advantages to be achieved while simultaneously achieving the other parameters.

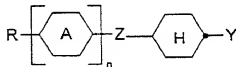
- 5 In the case of supertwisted (STN) cells, media are desired which enable greater multiplexability and/or lower threshold voltages and/or broader nematic phase ranges (in particular at low temperatures). To this end, a further increase in the available parameter
10 latitude (clearing point, smectic-nematic transition or melting point, viscosity, dielectric parameters, elastic parameters) is urgently desired.

- 15 The invention has the object of providing media for these MLC, TN or STN displays, in particular for reflective MLC displays, which do not have the abovementioned disadvantages or only do so to a reduced extent, and preferably simultaneously have very high specific resistance values and low threshold voltages
20 and low birefringence values.

- It has now been found that this object can be achieved if media according to the invention are used in displays.

- 25 The invention thus relates to a liquid-crystalline medium based on a mixture of polar compounds of positive dielectric anisotropy, characterized in that it comprises one or more compounds of general formula I

30



in which

- 35 R is H, an alkyl or alkenyl radical having 1 to 15 carbon atoms which is unsubstituted,

5

is a trans-1,4-cyclohexylene ring, in which,

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electro-optical use. They are stable chemically, thermally and to light.

In the media according to the invention comprising
5 compounds of the formula I, Y is preferably OCF_3 , OCHF_2 , CF_3 , CHF_2 , CF_2CHF_2 , CF_2Cl , OCF_2Cl , $\text{C}_2\text{H}_4\text{CHF}_2$, CF_2CHF_2 , $\text{CF}_2\text{CH}_2\text{CF}_3$, CHF_2 , OCH_2CHF_3 , OCH_2CHF_2 , OCF_2CHF_2 , $\text{O}(\text{CH}_2)_3\text{CF}_3$, $\text{OCH}_2\text{C}_2\text{F}_5$, $\text{OCH}_2\text{CF}_2\text{CHF}_2$, $\text{OCH}_2\text{C}_3\text{F}_7$, OCHF_2CF_3 , OC_2F_5 , $\text{OCF}_2\text{CHF}_2\text{CF}_3$, $\text{OCH}=\text{CF}_2$, $\text{OCF}=\text{CF}_2$, $\text{OCF}=\text{CF}_2\text{CF}_3$, $\text{OCF}=\text{CF}-\text{C}_2\text{F}_5$, $\text{CH}=\text{CHF}$, $\text{CH}=\text{CF}_2$,
10 $\text{CF}=\text{CF}_2$, CF_2OCF_3 , in particular OCF_3 and CF_3 .

Particular preference is given to compounds of the formula I in which ring A is a trans-1,4-cyclohexane ring or a dioxane ring.

15 If R is an alkyl radical and/or an alkoxy radical, this can be straight-chain or branched. It is preferably straight-chain, has 2, 3, 4, 5, 6 or 7 carbon atoms and accordingly is preferably ethyl, propyl, butyl, pentyl,
20 hexyl, heptyl, ethoxy, propoxy, butoxy, pentoxy, hexoxy or heptoxy, furthermore methyl, octyl, nonyl, decyl, undecyl, dodecyl, tridecyl, tetradecyl, pentadecyl, methoxy, octoxy, nonoxy, decoxy, undecoxy, dodecoxy, tridecoxy or tetradecoxy.

25 Oxaalkyl is preferably straight-chain 2-oxapropyl (= methoxymethyl), 2- (= ethoxymethyl) or 3-oxabutyl (= 2-methoxyethyl), 2-, 3- or 4-oxapentyl, 2-, 3-, 4- or 5-oxahexyl, 2-, 3-, 4-, 5- or 6-oxaheptyl, 2-, 3-,
30 4-, 5-, 6- or 7-oxaoctyl, 2-, 3-, 4-, 5-, 6-, 7- or 8-oxanonyl, or 2-, 3-, 4-, 5-, 6-, 7-, 8- or 9-oxadecyl.

If R is an alkyl radical in which one CH_2 group has been
35 replaced by $-\text{CH}=\text{CH}-$, this can be straight-chain or branched. It is preferably straight-chain and has 2 to 10 carbon atoms. Accordingly, it is in particular vinyl, prop-1- or -2-enyl, but-1-, -2- or -3-enyl, pent-1-, -2-, -3- or -4-enyl, hex-1-, -2-, -3-, -4- or

-5-enyl, hept-1-, -2-, -3-, -4-, -5- or -6-enyl, oct-1-, -2-, -3-, -4-, -5-, -6- or -7-enyl, non-1-, -2-, -3-, -4-, -5-, -6-, -7- or -8-enyl, dec-1-, -2-, -3-, -4-, -5-, -6-, -7-, -8- or -9-enyl.

5

If R is an alkyl radical in which one CH₂ group has been replaced by -O- and one has been replaced by -CO-, these are preferably adjacent. These thus contain an acyloxy group -CO-O- or an oxycarbonyl group -O-CO-.

10 These are preferably straight-chain and have 2 to 6 carbon atoms.

They are accordingly in particular acetoxy, propionyl-
oxy, butyryloxy, pentanoyloxy, hexanoyloxy, acetoxy-
15 methyl, propionyloxymethyl, butyryloxymethyl, pentanoyloxymethyl, 2-acetoxyethyl, 2-propionyloxyethyl, 2-butyryloxyethyl, 3-acetoxypropyl, 3-propionyloxypropyl, 4-acetoxybutyl, methoxycarbonyl, ethoxycarbonyl, propoxycarbonyl, butoxycarbonyl, pentoxycarbonyl, methoxycarbonylmethyl, ethoxycarbonylmethyl, propoxycarbonylmethyl, butoxycarbonylmethyl, 2-(methoxycarbonyl)ethyl, 2-(ethoxycarbonyl)ethyl, 2-(propoxycarbonyl)ethyl, 3-(methoxycarbonyl)propyl, 3-(ethoxycarbonyl)propyl or 4-(methoxycarbonyl)butyl.

25

If R is an alkyl radical in which one CH₂ group has been replaced by unsubstituted or substituted -CH=CH- and an adjacent CH₂ group has been replaced by CO or CO-O or O-CO, this can be straight-chain or branched. It is
30 preferably straight-chain and has 4 to 13 carbon atoms.

Accordingly, it is in particular acryloyloxymethyl, 2-acryloyloxyethyl, 3-acryloyloxypropyl, 4-acryloyloxybutyl, 5-acryloyloxypropyl, 6-acryloyloxyhexyl, 7-acryloyloxyheptyl, 8-acryloyloxyoctyl, 9-acryloyloxynonyl, 10-acryloyloxydecyl, methacryloyloxymethyl, 2-methacryloyloxyethyl, 3-methacryloyloxypropyl, 4-methacryloyloxybutyl, 5-methacryloyloxypropyl, 6-methacryloyloxyhexyl 7-methacryloyloxyheptyl, 8-methacryloyloxyoctyl or 9-methacryloyloxynonyl.

If R is an alkyl or alkenyl radical which is mono-substituted by CN or CF₃, this radical is preferably straight-chain. The substitution by CN or CF₃ is in any
5 desired position.

If R is an at least mono-halogen-substituted alkyl or alkenyl radical, this radical is preferably straight-chain and halogen is preferably F or Cl. In the case of
10 multiple substitution, halogen is preferably F. The resultant radicals also include perfluorinated radicals. In the case of monosubstitution, the fluorine or chlorine substituent can be in any desired position, but is preferably in the ω -position.

15 Compounds of the formula I which contain wing groups R which are suitable for polymerization reactions are suitable for the preparation of the liquid-crystalline polymers.

20 Compounds of the formula I containing branched wing groups R may occasionally be of importance owing to better solubility in the conventional liquid-crystalline base materials, but in particular as chiral
25 dopants if they are optically active. Smectic compounds of this type are suitable as components of ferro-electric materials.

Compounds of the formula I having S_A phases are suitable, for example, for thermally addressed displays.
30

Branched groups generally contain not more than one chain branch. Preferred branched radicals R are isopropyl, 2-butyl (= 1-methylpropyl), isobutyl
35 (= 2-methylpropyl), 2-methylbutyl, isopentyl (= 3-methylbutyl), 2-methylpentyl, 3-methylpentyl, 2-ethylhexyl, 2-propylpentyl, isopropoxy, 2-methylpropoxy, 2-methylbutoxy, 3-methylbutoxy, 2-methyl-

pentoxy, 3-methylpentoxy, 2-ethylhexoxy, 1-methylhexoxy or 1-methylheptoxy.

If R is an alkyl radical in which two or more CH₂ groups have been replaced by -O- and/or -CO-O-, this can be straight-chain or branched. It is preferably branched and has 3 to 12 carbon atoms. Accordingly, it is in particular biscarboxymethyl, 2,2-biscarboxyethyl, 3,3-biscarboxypropyl, 4,4-biscarboxybutyl, 5,5-biscarboxypentyl, 6,6-biscarboxyhexyl, 7,7-biscarboxyheptyl, 8,8-biscarboxyoctyl, 9,9-biscarboxynonyl, 10,10-biscarboxydecyl, bis(methoxycarbonyl)methyl, 2,2-bis(methoxycarbonyl)ethyl, 3,3-bis(methoxycarbonyl)propyl, 4,4-bis(methoxycarbonyl)butyl, 5,5-bis(methoxycarbonyl)pentyl, 6,6-bis(methoxycarbonyl)hexyl, 7,7-bis(methoxycarbonyl)heptyl, 8,8-bis(methoxycarbonyl)octyl, bis(ethoxycarbonyl)methyl, 2,2-bis(ethoxycarbonyl)ethyl, 3,3-bis(ethoxycarbonyl)propyl, 4,4-bis(ethoxycarbonyl)butyl or 5,5-bis(ethoxycarbonyl)hexyl.

Z is preferably a single bond, -COO- or a -CH₂CH₂-bridge.

25 The compounds of the formula I are prepared by methods known per se, as described in the literature (for example in the standard works, such as Houben-Weyl, Methoden der Organischen Chemie [Methods of Organic Chemistry], Georg-Thieme-Verlag, Stuttgart, to be
30 precise under reaction conditions which are known and suitable for said reactions. Use can also be made here of variants which are known per se, but are not mentioned here in greater detail. Furthermore, the compounds of the formula I can be prepared as described
35 in the patent applications DE 40 23 107 A1 and EP 0 418 362 A1.

The invention also relates to electro-optical displays (in particular STN or MLC displays having two plane-

parallel outer plates, which, together with a frame, form a cell, integrated non-linear elements for switching individual pixels on the outer plates, and a nematic liquid-crystal mixture of positive dielectric anisotropy and high specific resistance which is located in the cell) which comprise media of this type, and to the use of these media for electro-optical purposes.

The liquid-crystal mixtures according to the invention allow a significant increase in the parameter latitude which is available.

The achievable combinations of clearing point, viscosity at low temperature, thermal and UV stability, optical anisotropy and threshold voltage are far superior to the known materials from the prior art.

The requirement for a high clearing point, nematic phase at low temperature and low birefringence (Δn) and simultaneously a low threshold voltage has hitherto only been achieved inadequately. Although liquid-crystal mixtures such as, for example, MLC-6476 and MLC-6625 (Merck KGaA, Darmstadt, Germany) have comparable clearing points and low-temperature stabilities, they both have, however, much higher Δn values of about 0.075 and much higher threshold voltages of about ≥ 1.7 V or more.

While retaining the nematic phase down to -20°C , preferably down to -30°C , particularly preferably down to -40°C , and clearing points above 80°C , preferably above 90°C , particularly preferably above 100°C , the liquid-crystal mixtures according to the invention simultaneously allow birefringence values of ≤ 0.08 , preferably ≤ 0.07 , particularly preferably ≤ 0.065 , and a low threshold voltage, allowing excellent STN and MLC displays, in particular reflective MLC displays, to be achieved. In particular, the mixtures are characterized by low operating voltages. The TN thresholds are

usually below 1.9 V, preferably below 1.7 V, particularly preferably ≤ 1.5 V. Reflective displays in particular are distinguished by TN thresholds of < 1.5 V.

5 It goes without saying that a suitable choice of the components of the mixtures according to the invention also allows higher clearing points (for example above 110°C) to be achieved at the same time as lower
10 dielectric anisotropy values and thus higher threshold voltages, or lower clearing points to be achieved at the same time as higher dielectric anisotropy values (for example > 12) and thus lower threshold voltages (for example < 1.5 V) while retaining the other
15 advantageous properties. Likewise, mixtures of higher $\Delta\epsilon$ and thus lower thresholds can also be obtained at viscosities which are increased correspondingly little. The MLC displays according to the invention preferably operate at the first Gooch and Tarry transmission
20 minimum [C.H. Gooch and H.A. Tarry, Electron. Lett. 10, 2-4, 1974; C.H. Gooch and H.A. Tarry, Appl. Phys., Vol. 8, 1575-1584, 1975], where, besides particularly favourable electro-optical properties, such as, for example, high steepness of the characteristic line and
25 low angle dependence of the contrast (German Patent 30 22 818), a lower dielectric anisotropy is sufficient at the same threshold voltage as in an analogous display at the second minimum. Thus, significantly higher specific resistance values can be achieved using
30 the mixtures according to the invention at the first minimum than in the case of mixtures comprising cyano compounds. Through a suitable choice of the individual components and their proportions by weight, the person skilled in the art can set the birefringence necessary
35 for a specified layer thickness of the MLC display using simple routine methods. The requirements of reflective MLC displays are described, for example, in Digest of Technical Papers, SID Symposium 1998.

The rotational viscosity γ_1 at 20°C is preferably < 150 mPa.s, particularly preferably < 120 mPa.s. The nematic phase range is preferably at least 90°, in particular at least 100°. This range preferably extends at least from -20° to +80°.

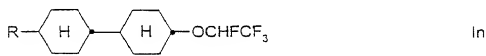
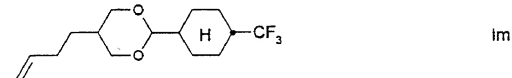
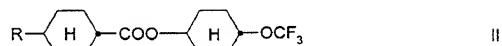
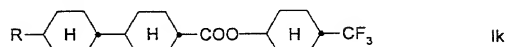
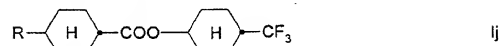
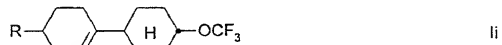
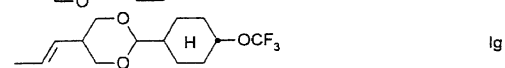
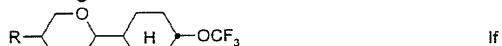
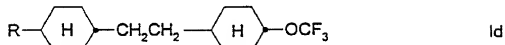
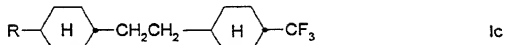
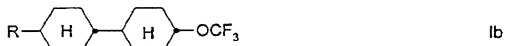
Measurements of the capacity holding ratio, also known as the voltage holding ratio (HR) [S. Matsumoto et al., Liquid Crystals 5, 1320 (1989); K. Niwa et al., Proc. SID Conference, San Francisco, June 1984, p. 304 (1984); G. Weber et al., Liquid Crystals 5, 1381 (1989)] have shown that mixtures according to the invention comprising compounds of the formula I have an adequate HR for MLC displays.

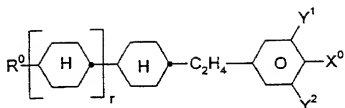
The media according to the invention preferably comprise a plurality (preferably two, three or more) of compounds of the formula I, i.e. the proportion of these compounds is 5-95%, preferably 10-60%, particularly preferably in the range 8-40%.

The individual compounds of the formulae I to XV and their sub-formulae which can be used in the media according to the invention are either known or can be prepared analogously to the known compounds.

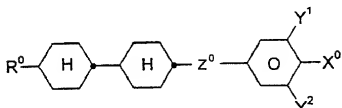
Preferred embodiments are indicated below.

- A mixture comprising one or more compounds of the formulae Ia to In:

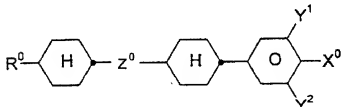




VI



VII



VIII

in which the individual radicals have the following meanings:

R^0 : n-alkyl, oxaalkyl, fluoroalkyl or alkenyl, in each case having up to 9 carbon atoms;

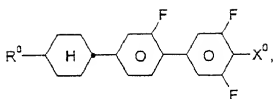
X^0 : F, Cl, halogenated alkyl or alkoxy having 1 to 6 carbon atoms or halogenated alkenyl having 2 to 6 carbon atoms;

Z^0 : $-C_4H_9-$, $-CF_2O-$, $-OCF_2-$, $-C_2F_4-$, $-CH_2O-$, $-OCH_2-$ or $-COO-$;

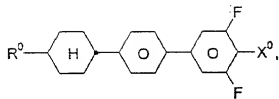
Y^1 , Y^2 , Y^3 and Y^4 : each, independently of one another, H or F;

r : 0 or 1.

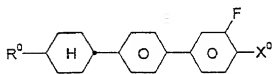
The compound of the formula IV is preferably



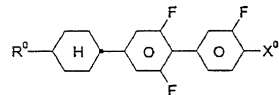
IVa



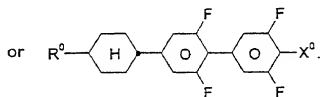
IVb



IVc

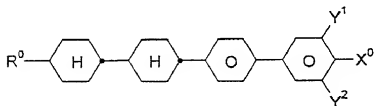


IVd

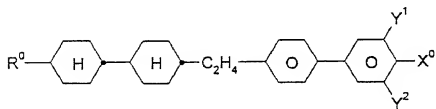


IVe

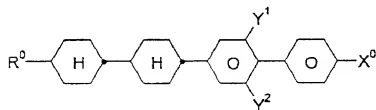
- 5 - The medium additionally comprises one or more compounds selected from the group consisting of the compounds of the general formulae IX to XV:



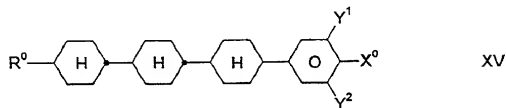
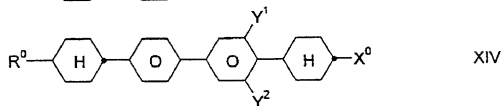
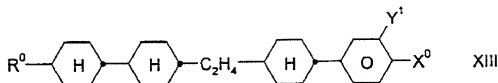
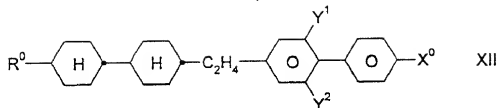
IX



X



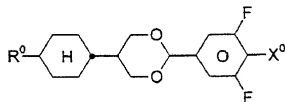
XI



5 in which R^0 , X^0 , Y^1 and Y^2 are each, independently of one another, as defined in Claim 2. X^0 is preferably F, Cl, CF_3 , OCF_3 or $OCHF_2$. R^0 is preferably alkyl, oxaalkyl, fluoroalkyl or alkenyl, each having up to 6 carbon atoms.

10

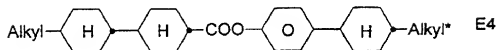
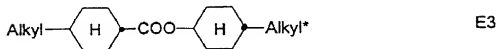
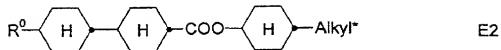
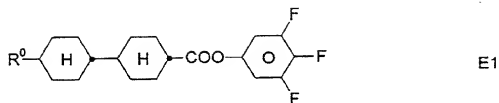
- The medium additionally comprises one or more compounds of the formula



15

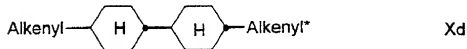
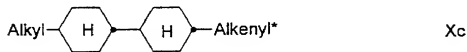
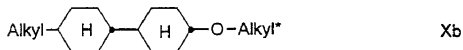
in which R^0 and X^0 are as defined above.

- The medium additionally comprises one or more ester compounds of the formulae E1 to E4:



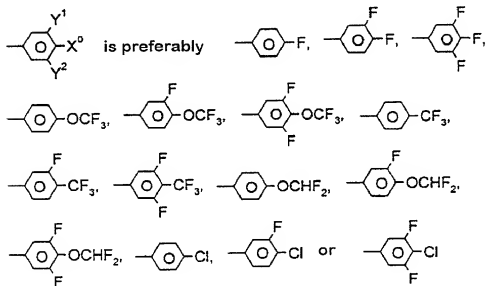
5 in which R^0 is as defined above.

- The medium additionally comprises one or more compounds of the formulae Xa to Xd:

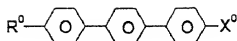


- The proportion of compounds of the formulae I to VIII in the mixture as a whole is at least 50% by weight;

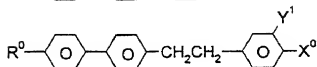
- The proportion of compounds of the formula I in the mixture as a whole is from 5 to 50% by weight;
- The proportion of compounds of the formulae II to VIII in the mixture as a whole is from 20 to 80% by weight;



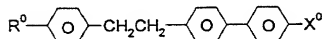
- 10 - The medium comprises compounds of the formulae II, III, IV, V, VI, VII or VIII;
- R⁰ is straight-chain alkyl or alkenyl having 2 to 7 carbon atoms;
- 15 - The medium essentially consists of compounds of the formulae I to VIII;
- The medium comprises a mixture of compounds of the formula I in which Y is CF₃ and/or OCF₃;
- 20 - The medium comprises further compounds, preferably selected from the following group consisting of the general formulae XVI to XIX;



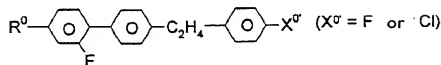
XVI



XVII



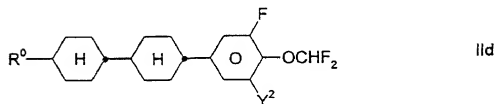
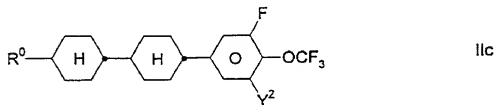
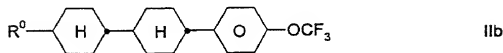
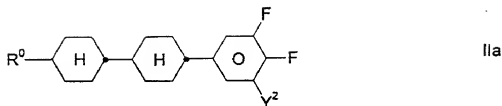
XVIII



XIX

in which R^0 and X^0 are as defined above, and the 1,4-phenylene rings may be substituted by CN, chlorine or fluorine. The 1,4-phenylene rings are preferably mono- or polysubstituted by fluorine atoms.

- The I : (II + III + IV + V + VI + VII + VIII) weight ratio is preferably 1 : 10 to 10 : 1;
- The medium essentially consists of compounds selected from the group consisting of the general formulae I to XV;
- The proportion of compounds of the formulae Xa to Xd in the mixture as a whole is 3-45% by weight, preferably 5-40% by weight, in particular 5-30% by weight;
- The proportion of compounds of the formula E1 in the mixture as a whole is 10-60% by weight, preferably 10-45% by weight, in particular 15-40% by weight;
- The compound of the formula II is preferably selected from the sub-formulae IIa to IId:



- 5 - The proportion of compounds of the formulae E2 and/or E3 in the mixture as a whole is 1-30% by weight, preferably 3-20% by weight, in particular 3-15% by weight;
- 10 - The proportion of compounds of the formula E4 in the mixture as a whole is $\leq 20\%$ by weight, in particular $\leq 10\%$ by weight.

It has been found that even a relatively small proportion of compounds of the formula I mixed with
 15 conventional liquid-crystal materials, but in particular with one or more compounds of the formulae II, III, IV, V, VI, VII and/or VIII results in a significant reduction in the threshold voltage and low birefringence values, where broad nematic phases with
 20 low smectic-nematic transition temperatures are simultaneously observed, improving the storage stability. Particular preference is given to mixtures

which, in addition to one or more compounds of the formula I, comprise one or more compounds of the formula IV, in particular compounds of the formula IVA in which X^0 is F or OCF_3 .

5

The compounds of the formulae I to VIII are colourless, stable and readily miscible with one another and with other liquid-crystalline materials.

- 10 The term "alkyl" or "alkyl*" preferably covers straight-chain and branched alkyl groups having 1-7 carbon atoms, in particular the straight-chain groups methyl, ethyl, propyl, butyl, pentyl, hexyl and heptyl. Groups having 2-5 carbon atoms are generally preferred.

15

The term "alkenyl" or "alkenyl*" preferably covers straight-chain and branched alkenyl groups having 2-7 carbon atoms, in particular the straight-chain groups. Particularly preferred alkenyl groups are

- 20 C_2 - C_7 -1E-alkenyl, C_4 - C_7 -3E-alkenyl, C_5 - C_7 -4-alkenyl, C_6 - C_7 -5-alkenyl and C_7 -6-alkenyl, in particular C_2 - C_7 -1E-alkenyl, C_4 - C_7 -3E-alkenyl and C_5 - C_7 -4-alkenyl. Examples of preferred alkenyl groups are vinyl, 1E-propenyl, 1E-butenyl, 1E-pentenyl, 1E-hexenyl,
25 1E-heptenyl, 3-butenyl, 3E-pentenyl, 3E-hexenyl, 3E-heptenyl, 4-pentenyl, 4Z-hexenyl, 4E-hexenyl, 4Z-heptenyl, 5-hexenyl, 6-heptenyl and the like. Groups having up to 5 carbon atoms are generally preferred.

- 30 The term "fluoroalkyl" preferably covers straight-chain groups having a terminal fluorine, i.e. fluoromethyl, 2-fluoroethyl, 3-fluoropropyl, 4-fluorobutyl, 5-fluoropentyl, 6-fluorohexyl and 7-fluoroheptyl. However, other positions of the fluorine are not
35 excluded.

The term "oxaalkyl" preferably covers straight-chain radicals of the formula $C_nH_{2n+1}-O-(CH_2)_m$, in which n and m

are each, independently of one another, from 1 to 6. n is preferably 1 and m is preferably from 1 to 6.

Through suitable choice of the meanings of R^0 and X^0 , the addressing times, the threshold voltage, the steepness of the transmission characteristic lines, etc., can be modified in the desired manner. For example, 1E-alkenyl radicals, 3E-alkenyl radicals, 2E-alkenyloxy radicals and the like generally result in short addressing times, improved nematic tendencies and a higher ratio of the elastic constants k_{33} (bend) and k_{11} (splay) compared with alkyl or alkoxy radicals. 4-Alkenyl radicals, 3-alkenyl radicals and the like generally give lower threshold voltages and smaller values of k_{33}/k_{11} compared with alkyl and alkoxy radicals.

A $-CH_2CH_2-$ group generally results in higher values of k_{33}/k_{11} compared with a single covalent bond. Higher values of k_{33}/k_{11} facilitate, for example, flatter transmission characteristic lines in TN cells with a 90° twist (in order to achieve grey shades) and steeper transmission characteristic lines in STN, SBE and OMI cells (higher multiplexability), and vice versa.

The optimum mixing ratio of the compounds of the formulae I and II + III + IV + V + VI + VII + VIII depends substantially on the desired properties, on the choice of the components of the formulae I, II, III, IV, V, VI, VII and/or VIII, and on the choice of any other components which may be present. Suitable mixing ratios within the range given above can easily be determined from case to case.

The total amount of compounds of the formulae I to XV in the mixtures according to the invention is not crucial. The mixtures can therefore comprise one or more further components in order to optimize various properties. However, the observed effect on the

addressing times and the threshold voltage is generally greater the higher the total concentration of compounds of the formulae I to XV.

5 In a particularly preferred embodiment, the media according to the invention comprise compounds of the formulae II to VIII (preferably II, III and/or IV, in particular IVa) in which X^0 is F, OCF_3 , $OCHF_2$, $OCH=CF_2$, $OCF=CF_2$ or OCF_2-CF_2H . A favourable synergistic
10 effect with the compounds of the formula I results in particularly advantageous properties. In particular, mixtures comprising compounds of the formula I and the formula IVa are distinguished by their low threshold voltages.

15 The construction of the STN or MLC display according to the invention from polarizers, electrode base plates and surface-treated electrodes corresponds to the conventional construction for displays of this type.
20 The term "conventional construction" is broadly drawn here and also covers all derivatives and modifications of the MLC display, in particular including matrix display elements based on poly-Si TFT or MIM and very particularly reflective displays.

25 A significant difference between the displays according to the invention and the conventional displays based on the twisted nematic cell consists, however, in the choice of the liquid-crystal parameters of the liquid-crystal layer.
30

The liquid-crystal mixtures which can be used in accordance with the invention are prepared in a manner conventional per se. In general, the desired amount of
35 the components used in a lesser amount is dissolved in the components making up the principal constituent, expediently at elevated temperature. It is also possible to mix solutions of the components in an organic solvent, for example in acetone, chloroform or

methanol, and to remove the solvent again after thorough mixing, for example by distillation. It is furthermore possible to prepare the mixtures in other conventional manners, for example by using premixtures, 5 for example homologue mixtures, or by using so-called "multi-bottle" systems.

The dielectrics may also comprise further additives known to the person skilled in the art and described in 10 the literature. For example, 0-15%, preferably 0-10%, of pleochroic dyes and/or chiral dopants can be added. The individual compounds added are employed in concentrations of from 0.01 to 6%, preferably from 0.1 to 3%. However, the concentration data for the other 15 constituents of the liquid-crystal mixtures, i.e. of the liquid-crystalline or mesogenic compounds, are given without taking into account the concentration of these additives.

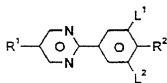
20 C denotes a crystalline phase, S a smectic phase, S_c a smectic C phase, N a nematic phase and I the isotropic phase.

In the present application and in the examples below, 25 the structures of the liquid-crystal compounds are indicated by means of acronyms, the transformation into chemical formulae taking place in accordance with Tables A and B below. All radicals C_nH_{2n+1} and C_mH_{2m+1} are straight-chain alkyl radicals having n and m carbon 30 atoms respectively. n and m are in each case, independently of one another, an integer, in particular 0, 1, 2, 3, 4, 5, 6, 7, 8, 9 or 10. The coding in Table B is self-evident. In Table A, only the acronym for the parent structure is given, followed, separated 35 from the acronym for the parent structure by a hyphen, by a code for the substituents R^1 , R^2 , L^1 and L^2 :

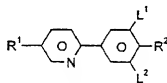
Code for R ¹ , R ² , L ¹ , L ²	R ¹	R ²	L ¹	L ²
nm	C _n H _{2n+1}	C _m H _{2m+1}	H	H
nOm	C _n H _{2n+1}	OC _m H _{2m+1}	H	H
nO.m	OC _n H _{2n+1}	C _m H _{2m+1}	H	H
n	C _n H _{2n+1}	CN	H	H
nN.F	C _n H _{2n+1}	CN	H	F
nF	C _n H _{2n+1}	F	H	H
nOF	OC _n H _{2n+1}	F	H	H
nCl	C _n H _{2n+1}	Cl	H	H
nF.F	C _n H _{2n+1}	F	H	F
nF.F.F	C _n H _{2n+1}	F	F	F
nCF ₃	C _n H _{2n+1}	CF ₃	H	H
nOCF ₃	C _n H _{2n+1}	OCF ₃	H	H
nOCF ₂	C _n H _{2n+1}	OCHF ₂	H	H
nS	C _n H _{2n+1}	NCS	H	H
rVsN	C ₇ H _{2r+1} -CH=CH-C ₈ H _{2s} -	CN	H	H
V-T	CH ₂ =CH	CF ₃	H	H
V2-T	CH ₂ =CH-C ₂ H ₄	CF ₃	H	H
1V-OT	CH ₃ -CH=CH	OCF ₃	H	H
rEsN	C ₇ H _{2r+1} -O-C ₈ H _{2s} -	CN	H	H
nAm	C _n H _{2n+1}	COOC _m H _{2m+1}	H	H
nOCCF ₂ .F.F	C _n H _{2n+1}	OCH ₂ CF ₂ H	F	F

Preferred mixture components are shown in Tables A and B.

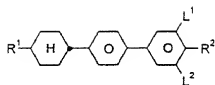
Table A:



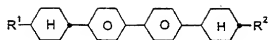
PYP



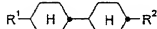
PYRP



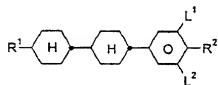
BCH



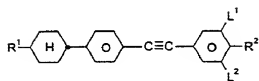
CBC



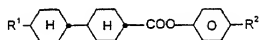
CCH



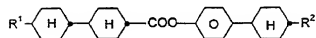
CCP



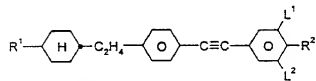
CPTP



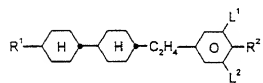
CP



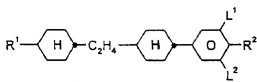
CCPC



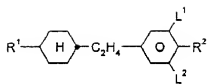
CEPT



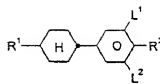
ECCP



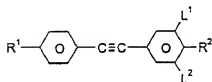
CECP



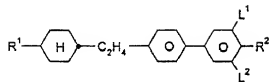
EPCH



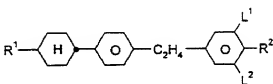
PCH



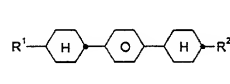
PTP



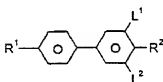
BECH



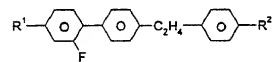
EBCH



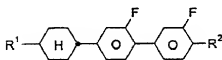
CPC



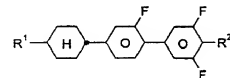
B



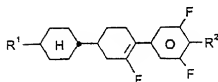
FET-nF



CGG

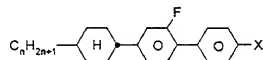


CGU

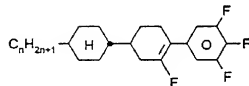


CFU

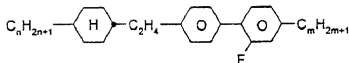
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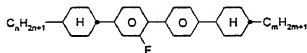
BCH-n.Fm



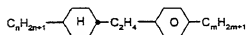
CFU-n-F



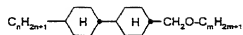
Inm



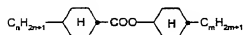
CBC-nmF



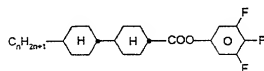
ECCP-nm



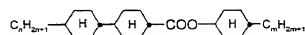
CCH-n1EM



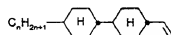
OS-nm



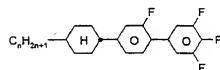
CCZU-n-F



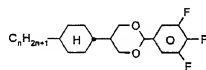
CH-nm



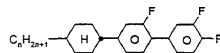
CC-5-V



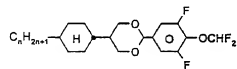
CGU-n-F



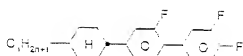
CDU-n-F



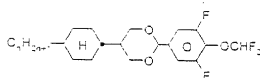
CGG-n-F



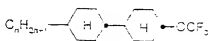
CDU-n-OD



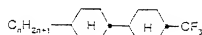
CGG-n-F



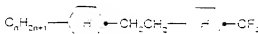
CDU-n-OD



CC-n-OT



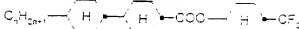
CCH-nCF₃



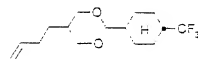
ECCH-nCF₃



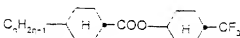
DC-n-T



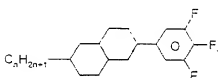
CCZC-n-T



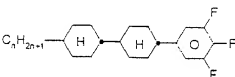
DC-V2-T



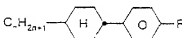
CZC-n-T



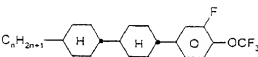
Dec-U-n-F



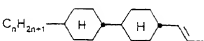
CCP-nF,F,F



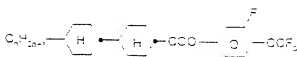
PCH-nF



CCP-nOCF₃,F



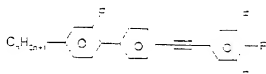
CC-n-V1



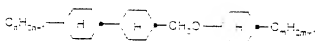
CCZG-n-OT



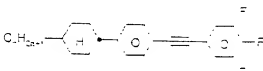
CC-n-OMT



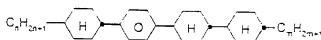
GPTU-n-F



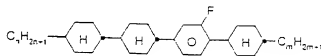
CCOC-n-m



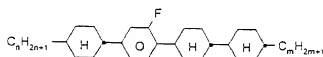
CPTU-n-F



CPCC-n-m



CCGC-n-m



CGCC-n-m

Particularly preferred liquid-crystalline mixtures are those comprising not only one, two or three compounds of the formula I but also one, two, three, four, five, six or more compounds from Table B.

The examples below are intended to illustrate the invention without representing a limitation. Above and below, percentages are percent by weight. All temperatures are given in degrees Celsius. m.p. denotes melting point, cl.p. clearing point. Furthermore, C = crystalline state, N = nematic phase, S = smectic phase and I = isotropic phase. The numbers between these

symbols are the transition temperatures. Δn denotes the optical anisotropy (589 nm, 20°C), and the flow viscosity η_{20} (mm²/sec) and rotational viscosity γ_1 (mPa·s) were each determined at 20°C.

5

V_{10} denotes the voltage for 10% transmission (viewing direction perpendicular to the plate surface). t_{on} denotes the switch-on time and t_{off} the switch-off time at an operating voltage corresponding to twice the value of V_{10} . Δn denotes the optical anisotropy, and n_o the refractive index. $\Delta\epsilon$ denotes the dielectric anisotropy ($\Delta\epsilon = \epsilon_2 - \epsilon_1$, where ϵ_2 denotes the dielectric constant parallel to the longitudinal axis of the molecules, and ϵ_1 denotes the dielectric constant perpendicular thereto). The electro-optical data were measured in a TN cell at the 1st minimum (i.e. at a $d \cdot \Delta n$ value of 0.5) at 20°C, unless expressly stated otherwise. The optical data were measured at 20°C, unless expressly stated otherwise.

20

Mixture Examples

Example 1 - Low Δn TFT mixture

CCH-3CF ₃	8.0%	S → N	< -40°C
CCH-5CF ₃	12.0%	Clearing point:	72°C
CC-5-V	5.0%	Δn [589 nm, 20°C]:	+0.0578
CCH-3O3	5.0%	$\Delta\epsilon$ [1 kHz, 20°C]:	+6.5
CCH-5O1	12.0%	γ_1 [mPa·s, 20°C]:	129
CCP-2F.F.F	12.0%	$d \cdot \Delta n$ [μ m, 20°C]:	0.5
CCP-3F.F.F	6.0%	$V_{10,0.20}$ [V]:	1.62
CCZU-2-F	6.0%		
CCZU-3-F	19.0%		
CCZU-5-F	6.0%		
CH-33	3.0%		
CH-35	3.0%		
CCPC-34	3.0%		

Example 2 - Low Δn TFT mixture

ECCH-5CF ₃	20.0%		
CC-5-V	5.0%	Clearing point:	+74°C
CCH-303	5.0%	Δn [589 nm, 20°C]:	+0.0585
CCH-501	12.0%	$\Delta \varepsilon$ [1 kHz, 20°C]:	+6.5
CCP-2F.F.F	12.0%	γ_1 [mPa.s, 20°C]:	141
CCP-3F.F.F	6.0%	$d \cdot \Delta n$ [μm , 20°C]:	0.5
CCZU-2-F	6.0%	Twist:	90°C
CCZU-3-F	19.0%	$V_{10,0,20}$ [V]:	1.69
CCZU-5-F	6.0%		
CH-33	3.0%		
CH-35	3.0%		
CCPC-34	3.0%		

5 Example 3 - Low Δn TFT mixture

CCH-3CF ₃	9.0%	S \rightarrow N	< -30°C
CCH-5CF ₃	12.0%	Clearing point:	78.5°C
CC-5-V	5.0%	Δn [589 nm, 20°C]:	+0.0646
CH-33	3.0%	$\Delta \varepsilon$ [1 kHz, 20°C]:	+8.8
CCP-2F.F.F	12.0%	γ_1 [mPa.s, 20°C]:	140
CCP-3F.F.F	12.0%	$d \cdot \Delta n$ [μm , 20°C]:	0.5
CCP-5F.F.F	5.0%	Twist:	90°C
CCP-2OCF ₃ .F	6.0%	$V_{10,0,20}$ [V]:	1.43
CCZU-2-F	6.0%		
CCZU-3-F	20.0%		
CCZU-5-F	6.0%		
CCPC-34	4.0%		

ECCH-5CF ₃	21.0%		
CC-5-V	5.0%	Clearing point:	+82.0°C
CH-33	3.0%	Δn [589 nm, 20°C]:	+0.0654
CCP-2F.F.F	12.0%	$\Delta \epsilon$ [1 kHz, 20°C]:	+8.5
CCP-3F.F.F	12.0%	γ_1 [mPa.s, 20°C]:	165
CCP-5F.F.F	5.0%	$d \cdot \Delta n$ [μm , 20°C]:	0.5
CCP-2OCF ₃ .F	6.0%	$V_{10,0,20}$ [V]:	1.49
CCZU-2-F	6.0%		
CCZU-3-F	20.0%		
CCZU-5-F	6.0%		
CCPC-34	4.0%		

CCH-3CF ₃	10.0%	S → N	< -30°C
CCH-5CF ₃	14.0%	Clearing point:	+72.0°C
CCH-3O ₂	7.0%	Δn [589 nm, 20°C]:	+0.0560
CCH-3O ₃	5.0%	V _{10, 0, 20} [V]:	1.87
CCH-5O ₁	12.0%		
CCP-2F.F.F	9.0%		
CCZU-2-F	6.0%		
CCZU-3-F	19.0%		
CCZU-5-F	6.0%		
CH-33	3.0%		
CH-35	3.0%		
CH-43	2.0%		
CCPC-33	2.0%		
CCPC-34	2.0%		

Example 6 - Low Δn TFT mixture

CCH-3CF ₃	8.0%	S → N	< -30°C
CCH-5CF ₃	12.0%	Clearing point:	+70.5°C
OS-33	6.0%	Δn [589 nm, 20°C]:	+0.0562
CCH-3O2	4.0%	V _{10,020} [V]:	1.80
CCH-3O3	5.0%		
CCH-5O1	12.0%		
CCP-2F.F.F	12.0%		
CCZU-2-F	6.0%		
CCZU-3-F	19.0%		
CCzU-5-F	6.0%		
CH-33	3.0%		
CH-35	3.0%		
CCPC-33	2.0%		
CCPC-34	2.0%		

5 Example 7 - Low Δn TFT mixture

CCH-3OCF ₃	10.0%		
CCH-5OCF ₃	14.0%	Clearing point:	+75.5°C
CCH-3O2	7.0%	Δn [589 nm, 20°C]:	+0.0572
CCH-3O3	7.0%	d· Δn [μm , 20°C]:	0.5
CCH-5O1	10.0%	V _{10,0,20} [V]:	1.74
CCP-2F.F.F	9.0%	Twist:	90°
CCZU-2-F	6.0%		
CCZU-3-F	19.0%		
CCZU-5-F	6.0%		
CH-33	3.0%		
CH-35	3.0%		
CH-43	3.0%		
CCPC-33	3.0%		

Example 8 - Low Δn TFT mixture

DC-V2-T	15.0%	S → N	< -30°C
CCH-3O2	15.0%	Clearing point:	+69.0°C
CH-34	4.0%	Δn [589 nm, 20°C]:	+0.0568
CCH-5O1	10.0%	$d \cdot \Delta n$ [μm , 20°C]:	0.49
CCP-2F.F.F	12.0%	$V_{10,0,20}$ [V]:	1.53
CCZU-2-F	6.0%	Twist:	90°
CCZU-3-F	20.0%		
CCZU-5-F	6.0%		
CH-33	3.0%		
CH-35	3.0%		
CH-43	3.0%		
CCPC-33	3.0%		

5 Example 9 - Low Δn TFT mixture

CCH-3O1	14.0%	S → N	< -30°C
CCH-5O1	11.0%	Clearing point:	+80.0°C
CCP-2F.F.F	10.0%	Δn [589 nm, 20°C]:	+0.0607
CCP-3F.F.F	13.0%	$d \cdot \Delta n$ [μm , 20°C]:	0.55
CCP-5F.F.F	5.0%	$V_{10,0,20}$ [V]:	1.53
CCZU-2-F	5.0%	Twist:	90°
CCZU-3-F	17.0%		
CCZU-5-F	5.0%		
CH-33	3.0%		
CH-35	3.0%		
CH-43	3.0%		
CCPC-33	3.0%		
CCH-3CF ₃	8.0%		

Example 10 - Reflective TN mixture

CCH-301	11.5%	S → N	< -30°C
CCP-2F.F.F	10.0%	Clearing point:	+80.0°C
CCP-3F.F.F	13.0%	Δn [589 nm, 20°C]:	+0.0654
CCP-5F.F.F	5.0%	$d \cdot \Delta n$ [μm , 20°C]:	0.55
CCZU-2-F	5.0%	$V_{10,0,20}$ [V]:	1.38
CCZU-3-F	16.0%	Twist:	90°
CCZU-5-F	4.0%		
CCP-2OCF ₂ .F.F	5.0%		
CCP-3OCF ₂ .F.F	6.0%		
CCP-5OCF ₂ .F.F	6.0%		
CH-33	3.0%		
CH-35	2.0%		
CH-43	2.5%		
CCH-3CF ₃	7.0%		
CCH-5CF ₃	4.0%		

5 Example 11 - Reflective TN mixture

CCH-301	11.0%	S → N	< -30°C
CCP-2F.F.F	10.0%	Clearing point:	+76.0°C
CCP-3F.F.F	13.0%	Δn [589 nm, 20°C]:	+0.0649
CCP-5F.F.F	5.0%	$d \cdot \Delta n$ [μm , 20°C]:	0.55
CCZU-2-F	4.0%	$V_{10,0,20}$ [V]:	1.39
CCZU-3-F	15.0%	Twist:	90°
CCZU-5-F	4.0%		
CCP-2OCF ₂ .F.F	6.0%		
CCP-3OCF ₂ .F.F	6.0%		
CCP-5OCF ₂ .F.F	7.0%		
CH-33	3.0%		
CH-43	3.0%		
CCH-3CF ₃	8.0%		
CCH-5CF ₃	5.0%		

CCH-301	6.0%	S → N	< -30°C
CCP-2F.F.F	10.0%	Clearing point:	+80.0°C
CCP-3F.F.F	13.0%	Δn [589 nm, 20°C]:	+0.0652
CCP-5F.F.F	5.0%	$d \cdot \Delta n$ [μm , 20°C]:	0.55
CCZU-2-F	5.0%	$V_{10,0,20}$ [V]:	1.43
CCZU-3-F	16.0%	Twist:	90°
CCZU-5-F	4.0%		
CCP-3OCF ₃ .F.F	6.0%		
CCP-5OCF ₃ .F.F	6.0%		
CCP-5OCF ₂ .F.F	5.0%		
CH-33	3.0%		
CH-35	2.0%		
CH-43	2.0%		
CCH-3CF ₃	10.0%		
CCH-5CF ₃	7.0%		

CCH-501	12.0%	S → N	< -40°C
CH-33	3.0%	Clearing point:	+81.5°C
CH-35	3.0%	Δn [589 nm, 20°C]:	+0.0604
CH-43	3.0%	$\Delta \varepsilon$ [1 kHz, 20°C]:	+8.4
CH-45	3.0%	γ_1 [mPa.s, 20°C]:	160
CCP-2F.F.F	9.0%	$d \cdot \Delta n$ [μm , 20°C]:	0.5
CCZU-2-F	6.0%	$V_{10,0,20}$ [V]:	1.42
CCZU-3-F	15.0%	Twist:	90°
CCZU-5-F	6.0%		
CDU-2-F	9.0%		
CDU-3-F	9.0%		
CDU-5-F	3.0%		
CCH-3CF ₃	7.0%		
CCH-5CF ₃	8.0%		
CCFC-34	4.0%		

CCH-301	4.0%	S → N	< -40°C
CCH-501	9.0%	Clearing point:	+80.5°C
CH-33	3.0%	Δn [589 nm, 20°C]:	+0.0640
CH-35	3.0%	$\Delta \epsilon$ [1 kHz, 20°C]:	+7.6
CH-43	2.0%	γ_1 [mPa.s, 20°C]:	161
CCP-2F.F.F	9.0%	$d \cdot \Delta n$ [μm , 20°C]:	0.5
CCP-3F.F.F	6.0%	$V_{10,0,20}$ [V]:	1.28
CCZU-2-F	6.0%	Twist:	90°
CCZU-3-F	15.0%		
CCZU-5-F	6.0%		
CDU-2-F	10.0%		
CDU-3-F	9.0%		
CDU-5-F	7.0%		
CCH-3CF ₃	7.0%		
CCPC-34	4.0%		

CCCH-30I	12.0%	S → N	< -20°C
CH-33	3.0%	Clearing point:	+93.0°C
CH-35	3.0%	Δn [589 nm, 20°C]:	+0.0653
CCP-4OCF ₃	8.0%	d· Δn [μm, 20°C]:	0.5
CCP-2F.F.F	12.0%	V _{10,0,20} [V]:	1.55
CCP-3F.F.F	12.0%	Twist:	90°
CCP-5F.F.F	6.0%		
CCZU-2-F	6.0%		
CCZU-3-F	13.0%		
CCZU-5-F	6.0%		
CZC-3-T	6.0%		
CCZC-3-T	10.0%		
CCPC-34	3.0%		

Example 16

CCH-3CF ₃	9.00 %	S → N	< -30 °C
CCH-5CF ₃	12.00 %	Clearing point:	+80.0 °C
CC-5-V	7.00 %	Δn [589 nm, 20 °C]:	+0.0648
CH-33	3.00 %	d· Δn [20 °C, μm]:	0.50
CCP-2F.F.F	12.00 %	Twist [°]:	90
CCP-3F.F.F	11.00 %	V _{10,0,20} [V]:	1.49
CCP-5F.F.F	6.00 %		
CCP-20CF ₃ .F	7.00 %		
CCZU-2-F	6.00 %		
CCZU-3-F	16.00 %		
CCZU-5-F	6.00 %		
CCPC-34	5.00 %		

Example 17

CCH-501	7.00 %	S → N	< -40 °C
CH-33	3.00 %	Clearing point:	+86.0 °C
CH-35	3.00 %	Δn [589 nm, 20 °C]:	+0.0645
CH-43	3.00 %	$\Delta \varepsilon$ [1kHz, 20 °C]:	+10.2
CCP-2F.F.F	7.00 %	d· Δn [20 °C, μm]:	0.50
CCP-3F.F.F	5.00 %	Twist [°]:	90
CCZU-2-F	6.00 %	V _{10,0,20} [V]:	1.36
CCZU-3-F	15.00 %		
CCZU-5-F	6.00 %		
CDU-2-F	9.00 %		
CDU-3-F	9.00 %		
CDU-5-F	6.00 %		
CCH-3CF ₃	7.00 %		
CCH-5CF ₃	8.00 %		
CCPC-34	3.00 %		
CCPC-33	3.00 %		

Example 18

CCH-501	12.00 %	S → N	< -40 °C
CH-33	3.00 %	Clearing point:	+82.5 °C
CH-35	3.00 %	Δn [589 nm, 20 °C]:	+0.0608
CH-43	3.00 %	d- Δn [20 °C, μm]:	0.50
CH-45	3.00 %	twist [°]:	90
CCP-2F.F.F	6.00 %	$V_{10,0,20}$ [V]:	1.42
CCP-3F.F.F	4.00 %		
CCZU-2-F	6.00 %		
CCZU-3-F	14.00 %		
CCZU-5-F	6.00 %		
CDU-2-F	8.00 %		
CDU-3-F	8.00 %		
CDU-5-F	5.00 %		
CCH-3CF ₃	8.00 %		
CCH-5CF ₃	7.00 %		
CCPC-34	4.00 %		

Example 19

CCH-301	5.00 %	S → N	< -40 °C
CCH-501	16.00 %	Clearing point:	+86.0 °C
CCP-2F.F.F	12.00 %	Δn [589 nm, 20 °C]:	+0.0622
CCP-3F.F.F	12.00 %	$\Delta \epsilon$ [1kHz, 20 °C]:	+4.8
CCP-5F.F.F	6.00 %	d- Δn [20 °C, μm]:	0.50
CCP-20CF ₃	5.00 %	twist [°]:	90
CCP-40CF ₃	6.00 %	$V_{10,0,20}$ [V]:	1.98
CCP-20CF ₃ .F	9.00 %		
CH-33	4.00 %		
CH-35	3.00 %		
CH-43	3.00 %		
CH-45	3.00 %		
CCPC-34	4.00 %		
CCH-3CF ₃	6.00 %		
CCH-5CF ₃	6.00 %		

Example 20

CH-33	3.00 %	S → N	< -40 °C
CH-35	2.00 %	Clearing point:	+76.5 °C
CCP-2F.F.F	10.00 %	Δn [589 nm, 20 °C]:	+0.0642
CCZU-2-F	6.00 %	d· Δn [20 °C, μm]:	0.50
CCZU-3-F	16.00 %	Twist [°]:	90
CCZU-5-F	6.00 %	V ₁₀ [V]:	1.22
CDU-2-F	9.00 %		
CDU-3-F	11.00 %		
CDU-5-F	8.00 %		
CCH-3CF ₃	11.00 %		
CCH-5CF ₃	11.00 %		
CCPC-33	4.00 %		
CCPC-34	3.00 %		

Example 21

CH-33	4.00 %	S → N	< -40 °C
CH-35	4.00 %	Clearing point:	+77.0 °C
CH-43	2.00 %	Δn [589 nm, 20 °C]:	+0.0628
CCP-2F.F.F	9.00 %	d· Δn [20 °C, μm]:	0.50
CCZU-2-F	6.00 %	Twist [°]:	90
CCZU-3-F	16.00 %	V ₁₀ [V]:	1.24
CCZU-5-F	6.00 %		
CDU-2-F	9.00 %		
CDU-3-F	11.00 %		
CDU-5-F	8.00 %		
CCH-3CF ₃	11.00 %		
CCH-5CF ₃	10.00 %		
CCPC-34	4.00 %		

Example 24

CCH-501	8.00 %	S → N	< -40 °C
CH-33	4.00 %	Clearing point:	+82.0 °C
CH-35	4.00 %	Δn [589 nm, 20 °C]:	+0.0620
CH-43	4.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCP-2F.F.F	9.00 %	Twist [°]:	90
CCZU-2-F	6.00 %	V_{10} [V]:	1.36
CCZU-3-F	16.00 %		
CCZU-5-F	6.00 %		
CDU-2-F	9.00 %		
CDU-3-F	11.00 %		
CDU-5-F	3.00 %		
CCH-3CF ₃	8.00 %		
CCH-5CF ₃	8.00 %		
CCPC-34	4.00 %		

Example 25

CCH-501	12.00 %	S → N	< -40 °C
CH-33	4.00 %	Clearing point:	+81.0 °C
CH-35	4.00 %	Δn [589 nm, 20 °C]:	+0.0610
CH-43	4.00 %	$\Delta \varepsilon$ [kHz, 20 °C]:	+8.9
CCP-2F.F.F	9.00 %	γ [mPa·s, 20 °C]:	154
CCZU-2-F	6.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCZU-3-F	16.00 %	Twist [°]:	90
CCZU-5-F	6.00 %	V_{10} [V]:	1.41
CDU-2-F	9.00 %		
CDU-3-F	11.00 %		
CCH-3CF ₃	7.00 %		
CCH-5CF ₃	8.00 %		
CCPC-34	4.00 %		

Example 26

CCH-303	5.00 %		
CCH-501	16.00 %	Clearing point:	+90.0 °C
CCP-2F.F.F	12.00 %	Δn [589 nm, 20 °C]:	+0.0628
CCP-3F.F.F	12.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCP-5F.F.F	6.00 %	Twist [°]:	90
CCP-20CF ₃	5.00 %	V_{10} [V]:	2.08
CCP-40CF ₃	7.00 %		
CCP-20CF ₃ .F	6.00 %		
CH-33	4.00 %		
CH-35	3.00 %		
CH-43	3.00 %		
CH-45	3.00 %		
CCPC-33	3.00 %		
CCPC-34	2.00 %		
CCH-3CF ₃	6.00 %		
CCH-5CF ₃	7.00 %		

Example 27

CCH-3CF ₃	8.00 %	S → N	< -40 °C
CCH-5CF ₃	8.00 %	Clearing point:	+87.5 °C
CCH-303	10.00 %	Δn [589 nm, 20 °C]:	+0.0628
CCH-501	6.00 %	$\Delta \epsilon$ [kHz, 20 °C]:	+7.3
CCP-2F.F.F	11.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCP-3F.F.F	10.00 %	Twist [°]:	90
CCP-5F.F.F	5.00 %	V_{10} [V]:	1.69
CCZU-2-F	6.00 %		
CCZU-3-F	16.00 %		
CCZU-5-F	6.00 %		
CCPC-33	3.00 %		
CCPC-34	2.00 %		
CH-33	3.00 %		
CH-35	3.00 %		
CH-43	3.00 %		

CCH-3CF ₃	6.00 %
CCH-5CF ₃	8.00 %
CCH-303	10.00 %
CCH-501	6.00 %
CCP-2F.F.F	10.00 %
CCP-3F.F.F	7.00 %
CCP-5F.F.F	5.00 %
CDU-2-F	10.00 %
CDU-3-F	10.00 %
CDU-5-F	8.00 %
CCPC-33	3.00 %
CCPC-34	3.00 %
CH-33	4.00 %
CH-35	4.00 %
CH-43	3.00 %
CH-45	3.00 %

S → N	< -40 °C
Clearing point:	+83.5 °C
Δn [589 nm, 20 °C]:	+0.0620
$d \cdot \Delta n$ [20 °C, μm):	0.50
Twist [°]:	90
V_{10} [V]:	1.58

CCH-303	15.00 %
CH-33	3.00 %
CH-35	3.00 %
CH-43	3.00 %
CH-45	3.00 %
CCP-2F F F	7.00 %
CCZU-2-F	6.00 %
CCZU-3-F	17.00 %
CCZU-5-F	6.00 %
CDU-2-F	10.00 %
CDU-3-F	9.00 %
CCH-3CF ₃	7.00 %
CCH-5CF ₃	7.00 %
CCPC-34	4.00 %

S \rightarrow N	< -30 °C
Clearing point:	+85.0 °C
Δn [589 nm, 20 °C]:	+0.0615
d· Δn [20 °C, μm]:	0.50
Twist [°]:	90
V ₀ [V]:	1.53

Example 30

CCH-303	11.00 %		
CCH-34	5.00 %	Clearing point:	+85.0 °C
CH-33	4.00 %	Δn [589 nm, 20 °C]:	+0.0607
CH-35	4.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CH-43	3.00 %	Twist [°]:	90
CH-45	3.00 %	V_{10} [V]:	1.55
CCP-2F.F.F	4.00 %		
CCZU-2-F	6.00 %		
CCZU-3-F	17.00 %		
CCZU-5-F	6.00 %		
CDU-2-F	10.00 %		
CDU-3-F	11.00 %		
CCH-3CF ₃	7.00 %		
CCH-5CF ₃	7.00 %		
CCPC-34	2.00 %		

Example 31

CCH-3CF ₃	6.00 %	S → N	< -20 °C
CCH-5CF ₃	7.00 %	Clearing point:	+84.0 °C
CCH-34	5.00 %	Δn [589 nm, 20 °C]:	+0.0617
CC-5-V	2.00 %		
CCH-303	11.50 %		
CCP-2F.F.F	9.00 %		
CCP-3F.F.F	5.00 %		
CCP-5F.F.F	3.00 %		
CDU-2-F	11.00 %		
CDU-3-F	11.00 %		
CDU-5-F	10.00 %		
CCPC-33	2.00 %		
CCPC-34	3.00 %		
CH-33	4.00 %		

CH-35	3.50 %
CH-43	3.50 %
CH-45	3.50 %

Example 32

CCH-303	12.00 %		
CCH-501	11.00 %	Clearing point:	+86.0 °C
CH-33	3.00 %	Δn [589 nm, 20 °C]:	+0.0610
CH-35	3.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CH-43	3.00 %	Twist [°]:	90
CH-45	3.00 %	V_{10} [V]:	1.61
CCZU-2-F	5.00 %		
CCZU-3-F	16.00 %		
CCZU-5-F	5.00 %		
CDU-2-F	9.00 %		
CDU-3-F	9.00 %		
CDU-5-F	7.00 %		
CCH-3CF ₃	5.00 %		
CCH-5CF ₃	5.00 %		
CCPC-34	4.00 %		

Example 33

CCH-303	14.00 %		
CCH-501	11.00 %	Clearing point:	+86.0 °C
CH-33	2.50 %	Δn [589 nm, 20 °C]:	+0.0612
CH-35	2.50 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CH-43	3.00 %	Twist [°]:	90
CH-45	3.00 %	V_{10} [V]:	1.61
CCZU-2-F	5.00 %		
CCZU-3-F	16.00 %		
CCZU-5-F	5.00 %		

CDU-2-F	9.00 %
CDU-3-F	9.00 %
CDU-5-F	8.00 %
CCH-3CF ₃	4.00 %
CCH-5CF ₃	4.00 %
CCPC-34	4.00 %

Example 34

CCH-301	8.00 %		
CCH-501	12.00 %	Clearing point:	+84.0 °C
CH-33	3.00 %	Δn [589 nm, 20 °C]:	+0.0614
CH-35	3.00 %	$\Delta \varepsilon$ [kHz, 20 °C]:	+8.3
CH-43	3.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CH-45	3.00 %	Twist [°]:	90
CCP-2F.F.F	9.00 %	V_{10} [V]:	1.48
CCZU-2-F	5.00 %		
CCZU-3-F	16.00 %		
CCZU-5-F	6.00 %		
CDU-2-F	8.00 %		
CDU-3-F	9.00 %		
CDU-5-F	4.00 %		
CCH-3CF ₃	3.00 %		
CCH-5CF ₃	4.00 %		
CCPC-34	4.00 %		

Example 35

CCH-301	13.00 %	S \rightarrow N	< -30.0 °C
CCH-35	6.00 %	Clearing point:	+88.5 °C
CCH-3CF ₃	8.00 %	Δn [589 nm, 20 °C]:	+0.0616
CCP-2F.F.F	10.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCP-3F F F	14.00 %	Twist [°]:	90
CCP-5F.F.F	6.00 %	V_{10} [V]:	1.63

CCZU-2-F	5.00 %
CCZU-3-F	13.00 %
CCZU-4-F	5.00 %
CCZU-5-F	5.00 %
CH-33	4.00 %
CH-35	4.00 %
CH-43	3.00 %
CH-45	4.00 %

Example 36

CCH-301	13.00 %	Clearing point:	+83.0 °C
CCH-35	6.00 %	Δn [589 nm, 20 °C]:	+0.0617
PCH-7F	2.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCH-3CF ₃	8.00 %	Twist [°]:	90
CCP-2F.F.F	10.00 %	V_o [V]:	1.51
CCP-3F.F.F	14.00 %		
CCP-5F.F.F	6.00 %		
CCZU-2-F	5.00 %		
CCZU-3-F	13.00 %		
CCZU-4-F	5.00 %		
CCZU-5-F	5.00 %		
CH-33	4.00 %		
CH-35	3.00 %		
CH-43	3.00 %		
CH-45	3.00 %		

Example 37

CCH-301	13.00 %	Clearing point:	+102.0 °C
CCH-35	6.00 %	Δn [589 nm, 20 °C]:	+0.0644
PCH-7F	2.00 %		
CCH-3CF ₃	8.00 %		
CCZU-2-F	5.00 %		

CCZU-3-F	13.00 %
CCZU-4-F	5.00 %
CCZU-5-F	5.00 %
CCZG-2-OT	10.00 %
CCZG-3-OT	14.00 %
CCZG-5-OT	6.00 %
CH-33	4.00 %
CH-35	3.00 %
CH-43	3.00 %
CH-45	3.00 %

Example 38

CCH-301	15.00 %
CCH-35	6.00 %
CCH-3CF ₃	8.00 %
CCP-2F.F.F	10.00 %
CCP-3F.F.F	14.00 %
CCP-5F.F.F	6.00 %
CCZU-2-F	5.00 %
CCZU-3-F	13.00 %
CCZU-4-F	5.00 %
CCZU-5-F	5.00 %
CH-33	4.00 %
CH-35	3.00 %
CH-43	3.00 %
CH-45	3.00 %

S → N	< -20 °C
Clearing point:	+84.5 °C
Δn [589 nm, 20 °C]:	+0.0613
$d \cdot \Delta n$ [20 °C, μm]:	0.50
Twist [°]:	90
V_{10} [V]:	1.58

Example 39

CCH-301	13.00 %
CCH-35	6.00 %
CCH-3CF ₃	8.00 %
CCP-2F.F.F	10.00 %
CCP-3F.F.F	14.00 %

S → N	< -20 °C
Clearing point:	+87.0 °C
Δn [589 nm, 20 °C]:	+0.0623
$d \Delta n$ [20 °C, μm]:	0.50
Twist [°]:	90

Example 40

Example 41

CCH-301	17.00 %	Clearing point:	+89.5 °C
CCH-35	6.00 %	Δn [589 nm, 20 °C]:	+0.0617
CCH-3CF ₃	8.00 %		
CCP-2F.F.F	5.00 %		
CCP-3F.F.F	5.00 %		

CCP-5F.F.F	5.00 %
CCZU-2-F	5.00 %
CCZU-3-F	13.00 %
CCZU-4-F	5.00 %
CCZU-5-F	5.00 %
CCZG-2-OT	5.00 %
CCZG-3-OT	5.00 %
CCZG-5-OT	5.00 %
CH-33	3.00 %
CH-35	3.00 %
CH-43	3.00 %
CH-45	2.00 %

Example 42

CCH-301	14.00 %
CCH-35	11.00 %
CCH-3CF ₃	8.00 %
CCP-2F.F.F	5.00 %
CCP-3F.F.F	10.00 %
CCP-5F.F.F	6.00 %
CCZU-2-F	5.00 %
CCZU-3-F	18.00 %
CCZU-4-F	8.00 %
CCZU-5-F	5.00 %
CH-33	3.00 %
CH-35	3.00 %
CH-43	2.00 %
CH-45	2.00 %

Clearing point: +85.5 °C
 Δn [589 nm, 20 °C]: +0.0601

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Clearing point:	+86.0 °C
Δn [589 nm, 20 °C]:	+0.0605
$d \Delta n$ [20 °C, μm]:	0.50
Twist [°]:	90
V_{10} [V]:	1.70

CCH-301	13.00 %
CCH-35	6.00 %
CCH-3CF ₃	8.00 %
CCP-2F.F.F	13.00 %
CCP-3F.F.F	17.00 %
CCP-5F.F.F	8.00 %
CCZU-2-F	5.00 %
CCZU-3-F	10.00 %
CCZU-5-F	5.00 %
CH-33	4.00 %
CH-35	4.00 %
CH-43	3.00 %
CH-45	4.00 %

Clearing point:	+86.0 °C
Δn [589 nm, 20 °C]:	+0.0615
$d \Delta n$ [20 °C, μm]:	0.50
Twist [°]:	90
V_{10} [V]:	1.67

Example 45

CCH-301	12.00 %	Clearing point:	+84.0 °C
CCH-35	10.00 %	Δn [589 nm, 20 °C]:	+0.0602
CCH-3CF ₃	11.00 %	d· Δn [20 °C, μm]:	0.50
CCP-2F.F.F	9.00 %	Twist [°]:	90
CCP-3F.F.F	12.00 %	V ₁₀ [V]:	1.66
CCP-5F.F.F	5.00 %		
CCZU-2-F	5.00 %		
CCZU-3-F	13.00 %		
CCZU-4-F	5.00 %		
CCZU-5-F	5.00 %		
CH-33	4.00 %		
CH-35	3.00 %		
CH-43	3.00 %		
CH-45	3.00 %		

Example 46

CCH-301	17.00 %	Clearing point:	+73.5 °C
CCH-35	10.00 %	Δn [589 nm, 20 °C]:	+0.0585
CCH-3CF ₃	11.00 %	d· Δn [20 °C, μm]:	0.50
CCP-2F.F.F	9.00 %	Twist [°]:	90
CCP-3F.F.F	12.00 %	V ₁₀ [V]:	1.59
CCP-5F.F.F	5.00 %		
CCZU-2-F	5.00 %		
CCZU-3-F	13.00 %		
CCZU-4-F	5.00 %		
CCZU-5-F	5.00 %		
CH-33	3.00 %		
CH-35	3.00 %		
CH-43	2.00 %		

CCH-301	14.00 %	S → N	< -40 °C
CCH-34	4.00 %	Clearing point:	+78.0 °C
CC-5-V	5.00 %	Δn [589 nm, 20 °C]:	+0.060
CCP-2F.F.F	10.00 %	$\Delta \varepsilon$ [kHz, 20 °C]:	6.6
CCP-3F.F.F	12.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCP-5F.F.F	6.00 %	Twist [°]:	90
CCZU-2-F	5.00 %	V_{10} [V]:	1.62
CCZU-3-F	16.00 %		
CCZU-5-F	5.00 %		
CCP-20CF ₃ F	2.00 %		
CCH-3CF ₃	10.00 %		
CH-33	3.00 %		
CH-35	3.00 %		
CH-43	3.00 %		
CH-45	2.00 %		

CCH-301	12.00 %	Clearing point:	+85.0 °C
CCH-35	10.00 %	Δn [589 nm, 20 °C]:	+0.0602
CCH-3CF ₃	6.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCH-5CF ₃	5.00 %	Twist [°]:	90
CCP-2F.F.F	9.00 %	V_{10} [V]:	1.72
CCP-3F.F.F	12.00 %		
CCP-5F.F.F	5.00 %		
CCZU-2-F	5.00 %		
CCZU-3-F	13.00 %		
CCZU-4-F	5.00 %		
CCZU-5-F	5.00 %		
CH-33	4.00 %		
CH-35	3.00 %		
CH-43	3.00 %		
CH-45	3.00 %		

Example 49

CCH-301	8.00 %	Clearing point:	+83.5 °C
CCH-501	5.00 %	Δn [589 nm, 20 °C]:	+0.0603
CCH-35	7.00 %	$\Delta \varepsilon$ [kHz, 20 °C]:	+7.3
CC-5-V	3.00 %	d· Δn [20 °C, μm]:	0.50
CCH-3CF ₃	6.00 %	Twist [°]:	90
CCH-5CF ₃	5.00 %	V_{10} [V]:	1.72
CCP-2F.F.F	7.00 %		
CCP-3F.F.F	8.00 %		
CCP-4F.F.F	6.00 %		
CCP-5F.F.F	5.00 %		
CCZU-2-F	5.00 %		
CCZU-3-F	8.00 %		
CCZU-4-F	5.00 %		
CCZU-5-F	5.00 %		
CCZG-2-OT	5.00 %		
CH-33	3.00 %		
CH-35	3.00 %		
CH-43	3.00 %		
CH-45	3.00 %		

Example 50

CCH-301	5.00 %	S → N	< -30 °C
CH-33	3.00 %	Clearing point:	+68.0 °C
CH-35	3.00 %	Δn [589 nm, 20 °C]:	+0.0602
CCP-2F F F	6.00 %	$\Delta \varepsilon$ [kHz, 20 °C]:	+10.3
CCZU-2-F	6.00 %	γ_1 [mPa·s, 20 °C]:	161
CCZU-3-F	16.00 %	d· Δn [20 °C, μm]:	0.50
CCZU-5-F	6.00 %	Twist [°]:	90
CDU-2-F	10.00 %	V_{10} [V]:	1.22
CDU-3-F	12.00 %		
CDU-5-F	8.00 %		

Example 51

Clearing point:	+74.0 °C
Δn [589 nm, 20 °C]:	+0.0631
$d \cdot \Delta n$ [20 °C, μm]:	0.50
Twist [°]:	90
V_{10} [V]:	1.21

CH-33	4.00 %
CCP-2F.F.F	10.00 %
CCP-3F.F.F	4.00 %
CCZU-2-F	6.00 %
CCZU-3-F	16.00 %
CCZU-5-F	6.00 %
CDU-2-F	9.00 %
CDU-3-F	11.00 %
CDU-5-F	7.00 %
CCH-3CF ₃	10.00 %
CCH-5CF ₃	12.00 %
CCPC-33	2.00 %
CCPC-34	3.00 %

Clearing point:	+69.0 °C
Δn [589 nm, 20 °C]:	+0.0625
$d \cdot \Delta n$ [20 °C, μm]:	0.50
Twist [°]:	90
V_{10} [V]:	1.16

Example 53

CCH-34	6.00 %	S → N	< -40 °C
CCH-3CF ₃	3.00 %	Clearing point:	+75.0 °C
CCH-5CF ₃	8.00 %	Δn [589 nm, 20 °C]:	+0.0644
CCP-2F.F.F	11.00 %	Δε [kHz, 20 °C]:	+10.1
CCP-3F.F.F	10.00 %	d·Δn [20 °C, μm]:	0.50
CCP-5F.F.F	6.00 %	Twist [°]:	90
CCP-20CF ₃ F	4.00 %	V ₁₀ [V]:	1.34
CCP-40CF ₃	8.00 %		
CDU-2-F	10.00 %		
CDU-3-F	12.00 %		
CDU-5-F	10.00 %		
CCOC-3-3	4.00 %		
CCOC-4-3	8.00 %		

Example 54

CCH-34	5.00 %	Clearing point:	+80.0 °C
CC-5-V	8.00 %	Δn [589 nm, 20 °C]:	+0.0642
CCH-3CF ₃	6.00 %	Δε [kHz, 20 °C]	+7.8
CCH-5CF ₃	8.00 %	d·Δn [20 °C, μm]:	0.50
CCP-2F.F.F	11.00 %	Twist [°]:	90
CCP-3F.F.F	11.00 %	V ₁₀ [V]:	1.58
CCP-5F.F.F	6.00 %		
CCZU-2-F	6.00 %		
CCZU-3-F	14.00 %		
CCZU-5-F	6.00 %		
CCP-20CF ₃ .F	8.00 %		
CCP-40CF ₃	4.00 %		
CCOC-4-3	5.00 %		
CCOC-3-3	2.00 %		

Example 57

CCH-34	5.00 %	S → N	< -40 °C
CC-5-V	6.00 %	Clearing point:	+80.5 °C
CCH-3CF ₃	6.00 %	$\Delta\epsilon$ [kHz, 20 °C]:	+7.9
CCH-5CF ₃	8.00 %	γ_1 [mPa·s, 20 °C]:	124
CCP-2F.F.F	11.00 %	d· Δn [20 °C, μm]:	0.50
CCP-3F.F.F	12.00 %	Twist [°]:	90
CCP-5F.F.F	5.00 %	V_{10} [V]:	1.56
CCZU-2-F	5.00 %		
CCZU-3-F	15.00 %		
CCZU-5-F	4.00 %		
CCP-20CF ₃ .F	10.50 %		
CCP-40CF ₃	6.50 %		
CCOC-4-3	4.00 %		
CCOC-3-3	2.00 %		

Example 58

CCH-301	10.00 %	S → N	< -40 °C
CCH-501	9.00 %	Clearing point:	+95.5 °C
CCH-35	5.00 %	Δn [589 nm, 20 °C]:	+0.0608
CC-5-V	12.00 %	V_{10} [V]:	2.32
CC-3-V1	5.00 %	d· Δn [20 °C, μm]:	0.50
CCH-3CF ₃	4.00 %	Twist [°]:	90
CCH-5CF ₃	5.00 %		
CCP-2F.F.F	6.00 %		
CDU-2-F	6.00 %		
CDU-3-F	8.00 %		
CCZU-3-F	7.00 %		
CCPC-33	4.00 %		
CCPC-34	5.00 %		
CCPC-35	4.00 %		

CCOC-3-3	3.00 %
CCOC-4-3	5.00 %
CCOC-3-5	2.00 %

Example 59

CCH-301	10.00 %	S → N	< -40 °C
CCH-501	8.00 %	Clearing point:	+95.0 °C
CCH-35	5.00 %	Δn [589 nm, 20 °C]:	+0.0607
CC-5-V	15.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CC-3-V1	4.00 %	Twist [°]:	90
CCH-3CF ₃	4.00 %	V_{10} [V]:	2.32
CCH-5CF ₃	4.00 %		
CCP-2F F.F	7.00 %		
CDU-2-F	7.00 %		
CDU-3-F	7.00 %		
CCZU-3-F	6.00 %		
CCPC-33	4.00 %		
CCPC-34	5.00 %		
CCPC-35	4.00 %		
CCOC-3-3	3.00 %		
CCOC-4-3	5.00 %		
CCOC-3-5	2.00 %		

Example 60

CCH-301	10.00 %	S → N	< -40 °C
CCH-501	11.00 %	Clearing point:	+95.5 °C
CCH-35	5.00 %	Δn [589 nm, 20 °C]:	+0.0609
CC-5-V	9.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCH-3CF ₃	4.00 %	Twist [°]:	90
CCH-5CF ₃	6.00 %	V_{10} [V]:	2.27
CCP-2F F.F	6.00 %		
CDU-2-F	6.00 %		

CDU-3-F	8.00 %
CCZU-3-F	7.00 %
CCOC-3-3	3.00 %
CCOC-4-3	5.00 %
CCOC-3-5	2.00 %
CCGC-3-3	2.00 %
CCGC-3-5	3.00 %
CGCC-2-3	5.00 %
CGCC-2-5	5.00 %
CH-43	3.00 %

Example 61

CCH-35	5.00 %
CC-3-V1	10.00 %
CC-5-V	18.00 %
CCH-3CF ₃	8.00 %
CCH-5CF ₃	10.00 %
CCP-2F.F.F	6.00 %
CDU-2-F	8.00 %
CDU-3-F	10.00 %
CGCC-2-3	5.00 %
CGCC-2-5	4.00 %
CCGC-3-2	5.00 %
CCGC-3-5	3.00 %
CCOC-3-3	3.00 %
CCOC-4-3	5.00 %

Clearing point:	+95.0 °C
Δn [589 nm, 20 °C]:	+0.0641
V_{10} [V]:	2.34
$d \cdot \Delta n$ [20 °C, μm]:	0.50
Twist [°]:	90

Example 62

CCH-301	9.00 %
CCH-501	10.00 %
CCH-35	5.00 %
CC-5-V	9.00 %

S \rightarrow N	< -40 °C
Clearing point:	+96.0 °C
Δn [589 nm, 20 °C]:	+0.0615
V_{10} [V]:	2.25

CCH-3CF ₃	7.00 %
CCH-5CF ₃	7.00 %
CCH-301	8.00 %
CCP-2F.F.F	6.00 %
CCP-3F.F.F	6.00 %
CCP-4F.F.F	5.00 %
CCP-5F.F.F	6.00 %
CCZU-2-F	8.00 %
CCZU-3-F	10.00 %
CCZU-4-F	9.00 %
CCZU-5-F	8.00 %
CCZG-3-OT	5.00 %
CCZG-5-OT	5.00 %
CCZG-2-OT	5.00 %
CH-33	3.00 %
CH-35	2.00 %

Clearing point:	+83.0 °C
Δn [589 nm, 20 °C]:	+0.0639
V_{10} [M]:	1.38
$d \cdot \Delta n$ [20 °C, μm]:	0.50
Twist [°]:	90

CCH-3CF ₃	4.00 %
CCH-5CF ₃	4.00 %
CCH-301	10.00 %
CCH-501	10.00 %
CCP-2F.F F	9.00 %
CCP-3F.F F	6.00 %
CCZU-3-F	15.00 %
CCZU-5-F	6.00 %
CDU-2-F	10.00 %
CDU-3-F	9.00 %
CDU-5-F	7.00 %
CCPC-33	5.00 %
CCPC-35	5.00 %

Clearing point:	+80.5 °C
Δn [589 nm, 20 °C]:	+0.0641
V_{10} [V]:	1.39
$d \Delta n$ [20 °C, μm]:	0.50
Twist [°]:	90

Example 66

CCH-3CF ₃	4.00 %	Clearing point:	+75.0 °C
CCH-5CF ₃	4.00 %	Δn [589 nm, 20 °C]:	+0.0633
CCH-301	10.00 %	V_{10} [V]:	1.34
CCH-501	10.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCP-2F.F.F	9.00 %	Twist [°]:	90
CCP-3F.F.F	6.00 %		
CCZU-3-F	15.00 %		
CCZU-5-F	6.00 %		
CDU-2-F	10.00 %		
CDU-3-F	9.00 %		
CDU-5-F	7.00 %		
CPCC-2-2	5.00 %		
CPCC-2-3	5.00 %		

Example 67

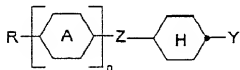
CCH-301	4.00 %	S → N	< -40 °C
CCH-501	5.50 %	Clearing point:	+88.0 °C
CCP-2F.F.F	10.00 %	Δn [589 nm, 20 °C]:	+0.0650
CCP-3F.F.F	12.00 %	$\Delta \varepsilon$ [kHz, 20 °C]:	+8.2
CCP-5F.F.F	5.00 %	$d \cdot \Delta n$ [20 °C, μm]:	0.50
CCZU-2-F	4.00 %	Twist [°]:	90
CCZU-3-F	17.00 %	V_{10} [V]:	1.52
CCZU-5-F	4.00 %		
CCP-20CF ₂ F.F	3.00 %		
CCP-30CF ₂ F.F	7.00 %		
CCP-50CF ₂ F.F	7.00 %		
CH-33	3.50 %		
CH-35	3.00 %		
CH-43	4.00 %		
CCH-3CF ₃	6.00 %		
CCH-5CF ₃	5.00 %		

CCH-301	12.00 %
CCH-501	8.00 %
CC-5-V	8.00 %
CCP-2F.F.F	10.00 %
CCP-3F.F.F	12.00 %
CCP-5F.F.F	5.00 %
CCZU-2-F	5.00 %
CCZU-3-F	17.00 %
CCZU-5-F	5.00 %
CH-33	3.00 %
CH-35	3.00 %
CH-43	3.00 %
CCH-3CF ₃	7.00 %
CCPC-33	2.00 %


S → N	< -30 °C
Clearing point:	+80.0 °C
Δn [589 nm, 20 °C]:	+0.0606
$\Delta \varepsilon$ [kHz, 20 °C]:	+6.3


Patent Claims

1. Liquid-crystalline medium based on a mixture of polar compounds of positive dielectric anisotropy, characterized in that it comprises one or more compounds of general formula I



in which

R is H, an alkyl or alkenyl radical having 1 to 15 carbon atoms which is unsubstituted, monosubstituted by CN or CF₃ or at least monosubstituted by halogen, where one or more CH₂ groups in these radicals may also, in each case independently of one another, be replaced by -O-, -S-, , -CO-, -CO-O-, -O-CO- or -O-CO-O- in such a way that O atoms are not linked directly to one another,

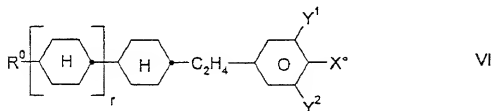
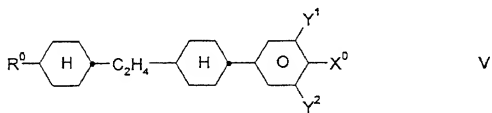
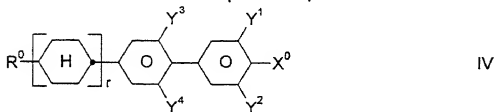
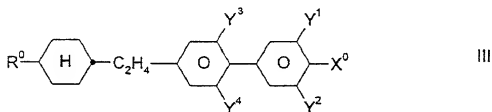
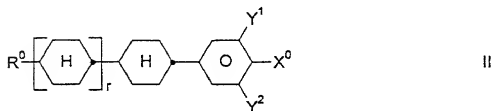
 is a trans-1,4-cyclohexylene ring, in which, in addition, one or two CH₂ groups may be replaced by -O- and/or -S-, or a cyclohexenylene ring,

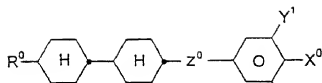
Y is halogenated alkyl, halogenated alkenyl, halogenated alkoxy or halogenated alkenyloxy having up to 6 carbon atoms,

Z is $-\text{CH}_2\text{O}-$, $-\text{OCH}_2-$, $-\text{CH}_2\text{CH}_2-$, $-\text{CH}=\text{CH}-$,
 $-\text{CF}_2\text{O}-$, $-\text{OCF}_2-$, $-\text{C}_2\text{F}_4-$ or a single bond,
 and

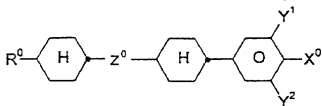
n is 1 or 2.

2. Medium according to Claim 1, characterized in that
 it additionally comprises one or more compounds
 selected from the group consisting of the general
 formulae II to VIII:





VII



VIII

in which the individual radicals have the following meanings:

R^0 : n-alkyl, oxaalkyl, fluoroalkyl or alkenyl, in each case having up to 7 carbon atoms;

X^0 : F, Cl, halogenated alkyl, alkenyl or alkoxy having 1 to 6 carbon atoms;

Z^0 : $-C_4H_9-$, $-CF_2O-$, $-OCF_2-$, $-C_2F_4-$, $-CH_2O-$, $-OCH_2-$ or $COO-$;

Y^1 , Y^2 , Y^3 and Y^4 : each, independently of one another, H or F

r : 0 or 1.

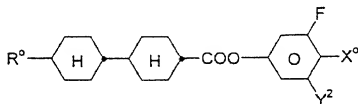
3. Medium according to Claim 2, characterized in that the proportion of compounds of the formulae I to VIII in the mixture as a whole is at least 50% by weight.

4. Medium according to Claim 1 or 2, characterized in that the proportion of compounds of the formula I

in the mixture as a whole is from 5 to 50% by weight.

5. Medium according to at least one of Claims 2 to 3,
5 characterized in that the proportion of compounds of the formulae II to VIII in the mixture as a whole is from 20 to 80% by weight.

6. Medium, according to Claim 1, characterized in
10 that it additionally comprises one or more compounds of the formula

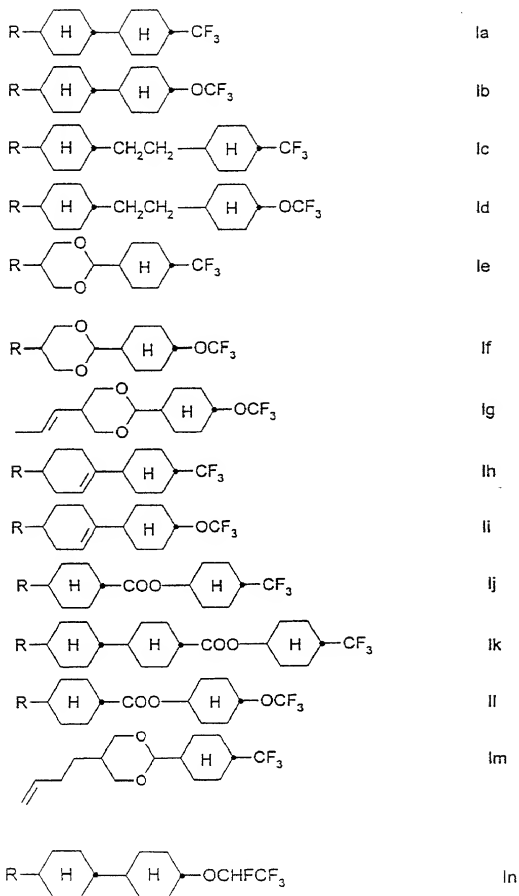


- 15 in which R°, X° and Y² are as defined in Claim 2.

7. Medium according to Claim 2 or Claim 6,
characterized in that X° is F or OCF₃, and Y² is H
or F.

- 20 8. Medium according to one of Claims 1 to 7,
characterized in that, in the compound of the
formula I, Y is OCF₃ or CF₃.

- 25 9. Medium according to one of Claims 1 to 8,
characterized in that the compound of the formula I
is selected from the group consisting of the
compounds Ia to In:



in which R is as defined in Claim 1.

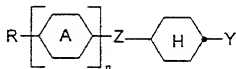
10. Use of the liquid-crystalline medium according to Claim 1 for electro-optical purposes.

5


11. Electro-optical liquid-crystal display containing a liquid-crystalline medium according to Claim 1.

Abstract

The invention relates to a liquid-crystalline medium based on a mixture of polar compounds of positive dielectric anisotropy, characterized in that it comprises one or more compounds of the general formula I



I

10 in which R, , Y, Z and n are as defined in Claim 1.

09868366.062404

Docket No.

Declaration and Power of Attorney For Patent Application

English Language Declaration

As a below named inventor, I hereby declare that:

My residence, post office address and citizenship are as stated below next to my name,

I believe I am the original, first and sole inventor (if only one name is listed below) or an original, first and joint inventor (if plural names are listed below) of the subject matter which is claimed and for which a patent is sought on the invention entitled

Liquid-crystalline medium

the specification of which

(check one)

☐ is attached hereto.

☒ was filed on 14.12.1999 as United States Application No. or PCT International Application Number PCT/EP99/009919 and was amended on _____

(if applicable)

I hereby state that I have reviewed and understand the contents of the above identified specification, including the claims, as amended by any amendment referred to above.

I acknowledge the duty to disclose to the United States Patent and Trademark Office all information known to me to be material to patentability as defined in Title 37, Code of Federal Regulations, Section 1.56.

I hereby claim foreign priority benefits under Title 35, United States Code, Section 119(a)-(d) or Section 365(b) of any foreign application(s) for patent or inventor's certificate, or Section 365(a) of any PCT International application which designated at least one country other than the United States, listed below and have also identified below, by checking the box, any foreign application for patent or inventor's certificate or PCT International application having a filing date before that of the application on which priority is claimed.

Prior Foreign Application(s)

Priority Not Claimed

<u>198 59 421.6</u>	<u>Germany</u>	<u>22.12.1998</u>	<input type="checkbox"/>
(Number)	(Country)	(Day/Month/Year Filed)	
_____	_____	_____	<input type="checkbox"/>
(Number)	(Country)	(Day/Month/Year Filed)	
_____	_____	_____	<input type="checkbox"/>
(Number)	(Country)	(Day/Month/Year Filed)	

00500000,0051014

I hereby claim the benefit under 35 U.S.C. Section 119(e) of any United States provisional application(s) listed below:

(Application Serial No.)

(Filing Date)

(Application Serial No.)

(Filing Date)

(Application Serial No.)

(Filing Date)

I hereby claim the benefit under 35 U. S. C. Section 120 of any United States application(s), or Section 365(c) of any PCT International application designating the United States, listed below and, insofar as the subject matter of each of the claims of this application is not disclosed in the prior United States or PCT International application in the manner provided by the first paragraph of 35 U.S.C. Section 112. I acknowledge the duty to disclose to the United States Patent and Trademark Office all information known to me to be material to patentability as defined in Title 37, C. F. R., Section 1.56 which became available between the filing date of the prior application and the national or PCT International filing date of this application:

(Application Serial No.)

(Filing Date)

(Status)
(patented, pending, abandoned)

(Application Serial No.)

(Filing Date)

(Status)
(patented, pending, abandoned)

(Application Serial No.)

(Filing Date)

(Status)
(patented, pending, abandoned)

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

POWER OF ATTORNEY: As a named inventor, I hereby appoint the following attorney(s) and/or agent(s) to prosecute this application and transact all business in the Patent and Trademark Office connected therewith. (list name and registration number)

I. William Millen (19,544)

John L. White (17,746)

Anthony J. Zelano (27,969)

Alan E.J. Branigan (20,565)

John R. Moses (24,983)

Harry B. Shubin (32,004)

Brion P. Heaney (32,542)

Diana Hamlet-King (33,302)

Richard J. Traverso (30,595)

Richard K. Kurtz (33,936)

John A. Sopp (33,103)

Richard M. Lebovitz (37,067)

John H. Thomas (33,460)

Send Correspondence to: MILLEN, WHITE, ZELANO & BRANIGAN, P.C.
2200 Clarendon Blvd., Suite 1400
Arlington, Virginia 22201

Direct Telephone Calls to: (name and telephone number)

John A. Sopp (703) 812-5315

Full name of sole or first inventor <u>Michael Heckmeier</u>	03. MAI 2001
Sole or first inventor's <u>Michael Heckmeier</u>	Date
Residence 64625 Bensheim	DEX
Citizenship Germany	
Post Office Address c/o MERCK KGaA	
64271 Darmstadt, Germany	

Full name of second inventor, if any <u>Brigitte Schuler</u>	03. MAI 2001
Second inventor's signature <u>Brigitte Schuler</u>	Date
Residence 63808 Haibach	
Citizenship Germany	DEX
Post Office Address c/o MERCK KGaA	
64271 Darmstadt, Germany	

Full name of third inventor, if any Kazuaki Tarumi	03. MAI. 2001
Third inventor's signature <i>Kazuaki Tarumi</i>	Date
Residence 64342 Seeheim	
Citizenship Japanese	
Post Office Address c/o MERCK KGaA	DEU
64271 Darmstadt, Germany	

Full name of fourth inventor, if any Peer Kirsch	03. MAI. 2001
Fourth inventor's signature <i>Peer Kirsch</i>	Date
Residence 64293 Darmstadt	
Citizenship Germany	
Post Office Address c/o MERCK KGaA	DEU
64271 Darmstadt, Germany	

Full name of fifth inventor, if any Volker Reiffenrath	03. MAI. 2001
Fifth inventor's signature <i>Volker Reiffenrath</i>	Date
Residence 64380 Roßdorf	
Citizenship Germany	
Post Office Address c/o MERCK KGaA	DEU
64271 Darmstadt, Germany	

Full name of sixth inventor, if any	
Sixth inventor's signature	Date
Residence	
Citizenship	
Post Office Address	